- Controlled Baseline
 - One Assembly/Test Site, One Fabrication Site
- Extended Temperature Performance of -40°C to 105°C
- Enhanced Diminishing Manufacturing Sources (DMS) Support
- Enhanced Product-Change Notification
- Qualification Pedigree[†]
- High-Performance Fixed-Point Digital Signal Processor (DSP) SM320C6201
 - 5-ns Instruction Cycle Time
 - 200-MHz Clock Rate
 - Eight 32-Bit Instructions/Cycle
 - 1600 MIPS
- VelociTI[™] Advanced Very Long Instruction
 Word (VLIW) TMS320C62x[™] DSP CPU Core
 - Eight Independent Functional Units:
 - Six Arithmetic Logic Units (ALUs) (32-/40-Bit)
 - Two 16-Bit Multipliers (32-Bit Results)
 - Load-Store Architecture With 32 32-Bit General-Purpose Registers
 - Instruction Packing Reduces Code Size
 - All Instructions Conditional
- Instruction Set Features
 - Byte-Addressable (8-, 16-, 32-Bit Data)
 - 32-Bit Address Range
 - 8-Bit Overflow Protection
 - Saturation
 - Bit-Field Extract, Set, Clear
 - Bit-Counting
 - Normalization

- 1M-Bit On-Chip SRAM
 - 512K-Bit Internal Program/Cache (16K 32-Bit Instructions)
 - 512K-Bit Dual-Access Internal Data (64K Bytes) Organized as Two Blocks for Improved Concurrency
- 32-Bit External Memory Interface (EMIF)
 - Glueless Interface to Asynchronous Memories: SRAM and EPROM
 - Glueless Interface to Synchronous Memories: SDRAM and SBSRAM
- Four-Channel Bootloading Direct-Memory-Access (DMA) Controller with an Auxiliary Channel
- 16-Bit Host-Port Interface (HPI)
 - Access to Entire Memory Map
- Two Multichannel Buffered Serial Ports (McBSPs)
 - Direct Interface to T1/E1, MVIP, SCSA Framers
 - ST-Bus-Switching Compatible
 - Up to 256 Channels Each
 - AC97-Compatible
 - Serial Peripheral Interface (SPI)
 Compatible (Motorola™)
- Two 32-Bit General-Purpose Timers
- Flexible Phase-Locked Loop (PLL) Clock Generator
- IEEE-1149.1 (JTAG[‡]) Boundary-Scan Compatible
- 352-Pin BGA Package (GJC Suffix)
- CMOS Technology
 - 0.18-μm/5-Level Metal Process
- 3.3-V I/Os, 1.8-V Internal



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

VelociTI and TMS320C62x are trademarks of Texas Instruments. Motorola is a trademark of Motorola, Inc.

[‡] IEEE Standard 1149.1-1990 Standard-Test-Access Port and Boundary Scan Architecture.

TEXAS INSTRUMENTS

[†] Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.

GJC/GJL 352-PIN BALL GRID ARRAY (BGA) PACKAGES (BOTTOM VIEW)

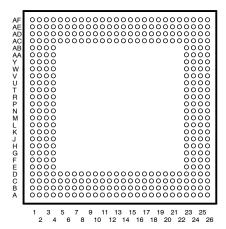


Table of Contents GJC BGA package (bottom view) 2 parameter measurement information 27 description 2 functional and CPU (DSP core) block diagram 4 synchronous-burst memory timing 32 CPU (DSP core) description 5 signal groups description 7 clock PLL 24 multichannel buffered serial port timing 47 DMAC, timer, power-down timing 56 absolute maximum ratings over operating case JTAG test-port timing 57 electrical characteristics over recommended ranges of supply voltage and operating case temperature 26

description

The TMS320C62x[™] DSPs (including the SM320C6201-EP[†]) are the fixed-point DSP family in the TMS320C6000[™] DSP platform. The C6201 device is based on the high-performance, advanced VelociTI[™] very-long-instruction-word (VLIW) architecture developed by Texas Instruments (TI), making these DSPs an excellent choice for multichannel and multifunction applications. With performance of up to 1600 MIPS at a clock rate of 200 MHz, the C6201 offers cost-effective solutions to high-performance DSP programming challenges. The C6201 DSP possesses the operational flexibility of high-speed controllers and the numerical capability of array processors. The processor has 32 general-purpose registers of 32-bit word length and eight highly independent functional units. The eight functional units provide six arithmetic logic units (ALUs) for a high degree of parallelism and two 16-bit multipliers for a 32-bit result. The C6201 can produce two multiply-accumulates (MACs) per cycle—for a total of 466 million MACs per second (MMACS). The C62x[™] DSP also has application-specific hardware logic, on-chip memory, and additional on-chip peripherals.

TMS320C6000, C6000, and C62x are trademarks of Texas Instruments.

Windows is a registered trademark of the Microsoft Corporation.

[†] The SM320C6201-EP device shall be referred to as C6201 throughout the remainder of this document.



description (continued)

The C6201 includes a large bank of on-chip memory and has a powerful and diverse set of peripherals. Program memory consists of a 64K-byte block that is user-configurable as cache or memory-mapped program space. Data memory of the C6201 consists of two 32K-byte blocks of RAM for improved concurrency. The peripheral set includes two multichannel buffered serial ports (McBSPs), two general-purpose timers, a host-port interface (HPI), and a glueless external memory interface (EMIF) capable of interfacing to SDRAM or SBSRAM and asynchronous peripherals.

The C62x[™] DSP has a complete set of development tools which includes: a new C compiler, an assembly optimizer to simplify programming and scheduling, and a Windows[™] debugger interface for visibility into source code execution.

device characteristics

Table 1 provides an overview of the C6201 DSP. The table shows significant features of each device, including the capacity of on-chip RAM, the peripherals, the execution time, and the package type with pin count.

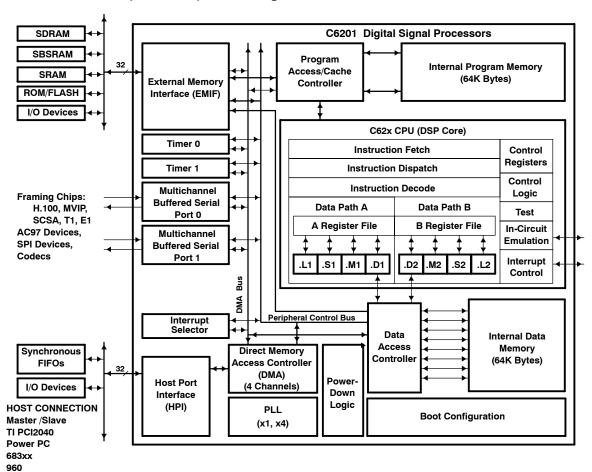
Table 1. Characteristics of the C6201 Processor

	HARDWARE FEATURES	C6201 (FIXED-POINT DSP)
	EMIF	1
	DMA	1
Peripherals	HPI	1
	McBSPs	2
	32-Bit Timers	2
	Size (Bytes)	72K
On-Chip Memory	Organization	512-Kbit Program Memory 512-Kbit Data Memory (organized as two blocks)
CPU ID+Rev ID	Control Status Register (CSR.[31:16])	0x0002
Frequency	MHz	200
Cycle Time	ns	5 ns (C6201-200)
Voltage	Core (V)	1.8
Voltage	I/O (V)	3.3
PLL Options	CLKIN frequency multiplier	Bypass (x1), x4
DCA Paskages	27 x 27 mm	352-Pin BGA (GJL)
BGA Packages	35 x 35 mm	352-Pin BGA (GJC)
Process Technology	μm	0.18 μm
Product Status	Product Preview (PP) Advance Information (AI) Production Data (PD)	PD
Device Part Numbers	(For more details on the C6000™ DSP part numbering, see Figure 4)	SM320C6201GJCA20EP

C6000 is a trademark of Texas Instruments.



functional and CPU (DSP core) block diagram



CPU (DSP core) description

The CPU fetches VelociTI™ advanced very-long instruction words (VLIW) (256 bits wide) to supply up to eight 32-bit instructions to the eight functional units during every clock cycle. The VelociTI™ VLIW architecture features controls by which all eight units do not have to be supplied with instructions if they are not ready to execute. The first bit of every 32-bit instruction determines if the next instruction belongs to the same execute packet as the previous instruction, or whether it should be executed in the following clock as a part of the next execute packet. Fetch packets are always 256 bits wide; however, the execute packets can vary in size. The variable-length execute packets are a key memory-saving feature, distinguishing the C62x CPU from other VLIW architectures.

The CPU features two sets of functional units. Each set contains four units and a register file. One set contains functional units .L1, .S1, .M1, and .D1; the other set contains units .D2, .M2, .S2, and .L2. The two register files each contain 1632-bit registers for a total of 32 general-purpose registers. The two sets of functional units, along with two register files, compose sides A and B of the CPU [see functional and CPU (DSP core) block diagram and Figure 1]. The four functional units on each side of the CPU can freely share the 16 registers belonging to that side. Additionally, each side features a single data bus connected to all the registers on the other side, by which the two sets of functional units can access data from the register files on the opposite side. While register access by functional units on the same side of the CPU as the register file can service all the units in a single clock cycle, register access using the register file across the CPU supports one read and one write per cycle.

Another key feature of the C62x CPU is the load/store architecture, where all instructions operate on registers (as opposed to data in memory). Two sets of data-addressing units (.D1 and .D2) are responsible for all data transfers between the register files and the memory. The data address driven by the .D units allows data addresses generated from one register file to be used to load or store data to or from the other register file. The C62x CPU supports a variety of indirect addressing modes using either linear- or circular-addressing modes with 5- or 15-bit offsets. All instructions are conditional, and most can access any one of the 32 registers. Some registers, however, are singled out to support specific addressing or to hold the condition for conditional instructions (if the condition is not automatically "true"). The two .M functional units are dedicated for multiplies. The two .S and .L functional units perform a general set of arithmetic, logical, and branch functions with results available every clock cycle.

The processing flow begins when a 256-bit-wide instruction fetch packet is fetched from a program memory. The 32-bit instructions destined for the individual functional units are "linked" together by "1" bits in the least significant bit (LSB) position of the instructions. The instructions that are "chained" together for simultaneous execution (up to eight in total) compose an execute packet. A "0" in the LSB of an instruction breaks the chain, effectively placing the instructions that follow it in the next execute packet. If an execute packet crosses the fetch packet boundary (256 bits wide), the assembler places it in the next fetch packet, while the remainder of the current fetch packet is padded with NOP instructions. The number of execute packets within a fetch packet can vary from one to eight. Execute packets are dispatched to their respective functional units at the rate of one per clock cycle and the next 256-bit fetch packet is not fetched until all the execute packets from the current fetch packet have been dispatched. After decoding, the instructions simultaneously drive all active functional units for a maximum execution rate of eight instructions every clock cycle. While most results are stored in 32-bit registers, they can be subsequently moved to memory as bytes or half-words as well. All load and store instructions are byte-, half-word, or word-addressable.

CPU (DSP core) description (continued)

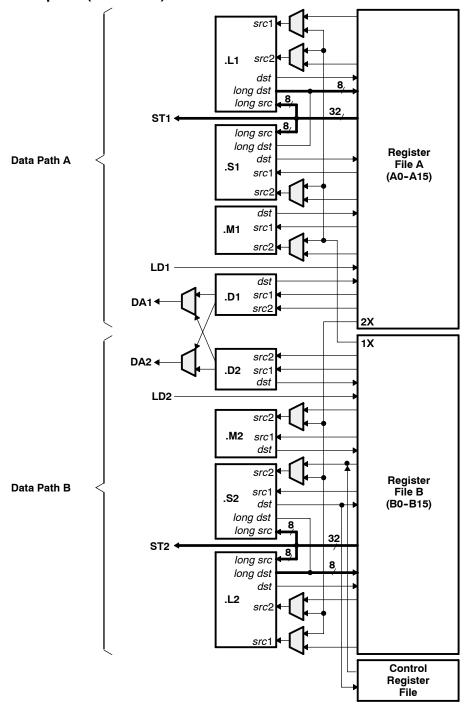


Figure 1. TMS320C62x CPU (DSP Core) Data Paths



signal groups description

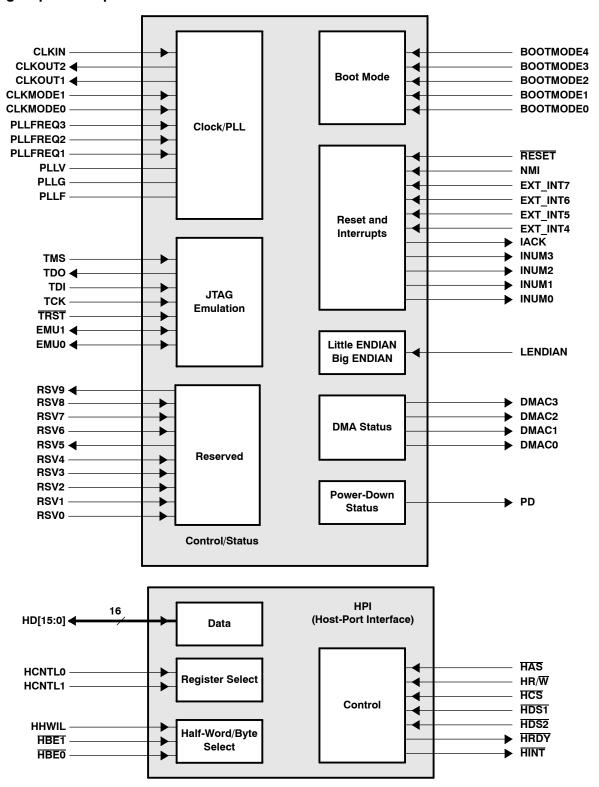


Figure 2. CPU (DSP Core) and Peripheral Signals



signal groups description (continued)

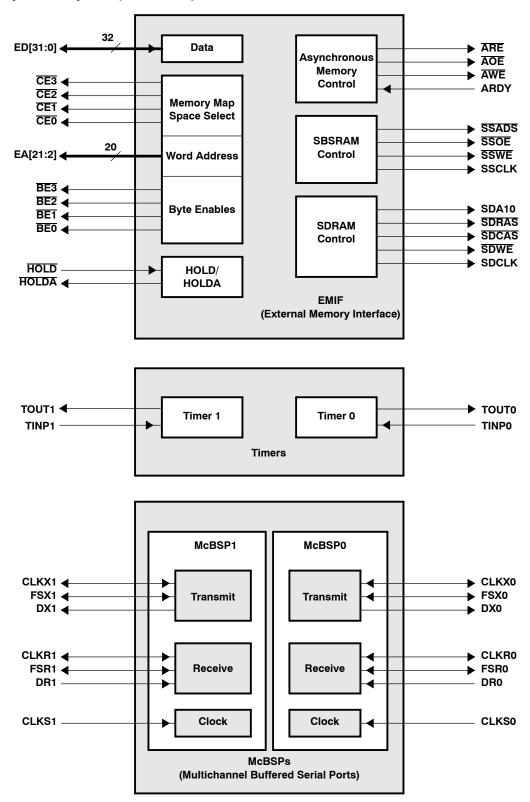


Figure 3. Peripheral Signals



Signal Descriptions

TYPE* DESCRIPTION	SIGNAL	SIGNAL PIN NO.						
CLOKIN C10 I Clock Input CLOKUT1 AF22 O Clock output at full device speed CLKOUT2 AF20 O Clock output at full device speed CLKMODE1 C6 CLKMODE1 C6 CLKMODE0 C5 CLKMODE0 C5 CLKMODE0 C5 PLLFREQ3 A9 PLLFREQ2 D111 I PLLFREQ0 D110 I D1 Af PLL analog V _{CC} connection for the low-pass filter PLLGF C12 Af PLL analog GND connection for the low-pass filter PLLGF C12 Af PLL analog GND connection for the low-pass filter PLLFREQ D110 TMS L3 I JTAG test port data out TMS L3 I JTAG test port data out TD1 R4 I JTAG test port data out TD1 R4 I JTAG test port data out TCK R3 I JTAG test port data in (features an internal pullup) TCK R3 I JTAG test port data in (features an internal pullup) TCK R3 I JTAG test port data in (features an internal pullup) TCK R3 I JTAG test port data in (features an internal pullup) TCK R3 I JTAG test port data in (features an internal pullup) TCK R3 I JTAG test port data in (features an internal pullup) TCK R3 I DEVICE Emulation pin 1, pullup with a dedicated 20-kQ resistor ⁴ RESET AND INTERRUPTS EXT_INT6 V2 EXT_INT6 V2 EXT_INT6 V3 I Sege-driven (rising edge) EXT_INT6 V4 I CACK V2 O Interrupt acknowledge for all active interrupts serviced by the CPU INUM3 AA1 INUM0 AA2 INUM0 AA2 INUM0 AA2 INUM0 AA3 I If high, LENDIAN selects little-endian byte-half-word addressing order within a word fill flow, LENDIAN selects big-endian addressing POWER-DOWN STATUS			TYPE†	DESCRIPTION				
CLKOUT1 AF22 O Clock output at full device speed CLKOUT2 AF20 O Clock output at half of device speed CLKMODE1 C6 CLKMODE0 C5 CLKMODE0 C5 CS Clock mode selects Selects whether the CPU clock frequency = input clock frequency x4 or x1 For more details on the QLC and QLL CLKMODE pins and the PLL multiply factors, see the Clock PLL section of this data sheet. PLLFREQ3 A9 PLLFREQ3 D11 PLLFREQ D11 PLLFREQ D11 PLLFREQ D11 PLLFREQ D12 A\$ PLL frequency range (3, 2, and 1) The target range for CLKOUT1 frequency is determined by the 3-bit value of the PLLFREQ pins. PLLFREQ D12 A\$ PLL analog QND connection for the low-pass filter PLLF A11 A\$ PLL lanalog QND connection for the low-pass filter PLLF A11 A\$ PLL lanalog NDC connection for the low-pass filter PLLF A11 A\$ PLL lanalog NDC connection for the low-pass filter PLT A11 A\$ PLL set part data out TAGE test port mode select (features an internal pullup) TOW								
CLKOUT2 AF20 O Clock output at half of device speed CLKMODE1 C8 LI CLKMODE0 C5 LI CLKMODE0 LI LI LI CLKMODE0 LI LI LI CLKMODE0 LI LI CLKMODE0 LI LI CLKMODE0 LI LI CLKMODE0 LI LI LI LI CLKMODE0 LI CLKMODE0 LI LI CLKMODE0 LI CLKMODE0 LI LI	CLKIN	C10	ı	Clock Input				
CLKOUT2 AF20 O Clock output at half of device speed CLKMODE1 C8 LI CLKMODE0 C5 LI CLKMODE0 LI LI LI CLKMODE0 LI LI LI CLKMODE0 LI LI CLKMODE0 LI LI CLKMODE0 LI LI CLKMODE0 LI LI LI LI CLKMODE0 LI CLKMODE0 LI LI CLKMODE0 LI CLKMODE0 LI LI	CLKOUT1	AF22	0	· ·				
CLKMODE1 C6 Clck mode selects	CLKOUT2		0	·				
- Selects whether the CPU clock frequency = input dock frequency x4 or x1 For more details on the GJC and GJL CLKMODE pins and the PLL multiply factors, see the Clock PLL section of this data sheet. PLLFREQ2 D11 PLLFREQ1 B10 PLLFREQ2 B11 PLLFREQ1 B10 PLLFREQ2 B11 PLLFREQ1 B10 PLLFREQ1 B10 PLLFREQ2 B11 PLLFREQ1 B10 PLLFREQ2 B11 PLLFREQ1 B10 PLLFREQ2 B11 PLLFREQ2 B11 PLLFREQ2 B11 PLLFREQ1 B10 PLLFREQ2 B11 PLLFREQ2 B11 PLLFREQ2 B11 PLLFREQ2 B11 PLLFREQ2 B11 PLLFREQ2 B11 PLLFREQ1 B10 PLLFREQ2 B11 PLLFREQ1 B10 PLLFREQ1 B10 PLLFREQ1 B10 PLLFREQ2 B11 PLLFREQ1 B10	OLIMODE1	00						
CLKMODEO CS See the Clack PLL section of this data sheet. PLLFREQ3 A9 PLLFREQ2 D11 PLLFREQ1 B10 PLLFREQ1 B10 PLLFREQ pins. PLLG† C12 A5 PLL analog V _{CC} connection for the low-pass filter PLLG† C12 A5 PLL analog V _{CC} connection for the low-pass filter PLLF PLLF A11 A5 PLL analog V _{CC} connection for the low-pass filter PLLF PLLF A11 A5 PLL low-pass filter connection to external components and a bypass capacitor JTAG EMULATION TMS L3 I JTAG test port data out TDI R4 I JTAG test port data out TDI R4 I JTAG test port data in (features an internal pullup) TCK R3 I JTAG test port data in (features an internal pullup) TCK R3 I JTAG test port data out TRST T1 I JTAG test port clock TRST T1 I JTAG test port deata out TWI EMU1 Y1 I VO/Z Emulation pin 1, pullup with a dedicated 20+\(\Omega\) resistor \(\frac{1}{2}\) EMU0 W3 IVOZ Emulation pin 0, pullup with a dedicated 20+\(\Omega\) resistor \(\frac{1}{2}\) EMESET NO INTERRUPTS RESET AND INTERRUPTS RESET AND INTERRUPTS RESET AND INTERRUPTS EXT_INT7 U3 EXT_INT7 U3 EXT_INT7 U3 EXT_INT4 U4 IACK Y2 O Interrupt acknowledge for all active interrupts polarity register bits (EXTPOL_[3:0]) EXT_INT4 U4 IACK Y2 O Interrupt acknowledge for all active interrupts serviced by the CPU NOMM3 AA1 INUM2 INUM2 INUM3 INUM2 INUM4 INUM4 INUM5 INUM6 AB1 I fligh, LENDIAN selects bitg-endian addressing order within a word lift low, LENDIAN selects bitg-endian addressing POWER-DOWN STATUS	CLKMODE1	C6		Selects whether the CPU clock frequency = input clock frequency x4 or x1				
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TDI R4 I JTAG test port data in (features an internal pullup) TCK R3 I JTAG test port clock TRST T1 I J JTAG test port reset (features an internal pulldown) EMU1 Y1 I/O/Z Emulation pin 1, pullup with a dedicated 20-kΩ resistor [§] EMU0 W3 I/O/Z Emulation pin 0, pullup with a dedicated 20-kΩ resistor [§] RESET NOINTERRUPTS RESET K2 I Device reset Nonmaskable interrupt • Edge-driven (rising edge) EXT_INT7 U3 EXT_INT6 V2 I Edge-driven • Polarity independently selected via the external interrupt polarity register bits (EXTPOL.[3:0]) INUM3 AA1 INUM2 W4 O Interrupt acknowledge for all active interrupts (not just external) • Encoding order follows the interrupts-service fetch-packet ordering LENDIAN H3 I If high, LENDIAN selects little-endian byte/half-word addressing order within a word if low, LENDIAN selects big-endian addressing	TMS	L3	I	JTAG test port mode select (features an internal pullup)				
TCK R3 I JTAG test port clock TRST T1 I JTAG test port reset (features an internal pulldown) EMU1 Y1 I/O/Z Emulation pin 1, pullup with a dedicated 20-kΩ resistor [¶] EMU0 W3 I/O/Z Emulation pin 0, pullup with a dedicated 20-kΩ resistor [¶] RESET AND INTERRUPTS RESET K2 I Device reset NMI L2 I Nonmaskable interrupt • Edge-driven (rising edge) EXT_INT7 U3 EXT_INT6 V2 EXT_INT5 W1 Polarity independently selected via the external interrupt polarity register bits (EXTPOL_[3:0]) INUM3 AA1 INUM2 W4 INUM1 AA2 INUM0 AB1 I If high, LENDIAN selects little-endian byte/half-word addressing order within a word If low, LENDIAN selects big-endian addressing POWER-DOWN STATUS	TDO	W2	O/Z	JTAG test port data out				
TRST T1 I JTAG test port reset (features an internal pulldown) EMU1 Y1 I/O/Z Emulation pin 1, pullup with a dedicated 20-kΩ resistor [§] EMU0 W3 I/O/Z Emulation pin 0, pullup with a dedicated 20-kΩ resistor [§] RESET AND INTERRUPTS RESET K2 I Device reset NMI L2 I Nonmaskable interrupt • Edge-driven (rising edge) EXT_INT7 U3 EXT_INT6 V2 EXT_INT5 W1 • Edge-driven • Polarity independently selected via the external interrupt polarity register bits (EXTPOL.[3:0]) IACK Y2 O Interrupt acknowledge for all active interrupts serviced by the CPU INUM3 AA1 INUM2 W4 INUM0 AB1 I f high, LENDIAN selects little-endian byte/half-word addressing order within a word If low, LENDIAN selects big-endian addressing POWER-DOWN STATUS	TDI	R4	I	JTAG test port data in (features an internal pullup)				
EMU1 Y1 I/O/Z Emulation pin 1, pullup with a dedicated 20-kΩ resistor [¶] EMU0 W3 I/O/Z Emulation pin 0, pullup with a dedicated 20-kΩ resistor [¶] RESET AND INTERRUPTS RESET AND INTERRUPTS RESET AND INTERRUPTS RESET K2 I Device reset Nonmaskable interrupt • Edge-driven (rising edge) EXT_INT7 U3 EXT_INT8 V2 EXT_INT5 W1 EXT_INT5 W1 IACK Y2 O Interrupt acknowledge for all active interrupts serviced by the CPU INUM3 AA1 INUM2 W4 INUM1 AA2 INUM0 AB1 I high, LENDIAN selects little-endian byte/half-word addressing order within a word If low, LENDIAN selects big-endian addressing POWER-DOWN STATUS	TCK	R3	I	JTAG test port clock				
RESET K2 I Device reset NMI L2 I Nonmaskable interrupt • Edge-driven (rising edge) EXT_INT7 U3 EXT_INT6 V2 EXT_INT5 W1 Polarity independently selected via the external interrupt polarity register bits (EXTPOL.[3:0]) INUM3 AA1 INUM2 W4 INUM1 AA2 INUM0 AB1 I I High, LENDIAN selects little-endian byte/half-word addressing order within a word if low, LENDIAN selects big-endian addressing POWER-DOWN STATUS	TRST	T1	I	JTAG test port reset (features an internal pulldown)				
RESET AND INTERRUPTS RESET K2 I Device reset Nonmaskable interrupt • Edge-driven (rising edge) EXT_INT7 U3 EXT_INT6 V2 EXT_INT5 W1 • Edge-driven • Polarity independently selected via the external interrupt polarity register bits (EXTPOL.[3:0]) INUM3 AA1 INUM2 W4 INUM1 AA2 INUM0 AB1 RESET AND INTERRUPTS I Device reset Nonmaskable interrupt • Edge-driven • Polarity independently selected via the external interrupt polarity register bits (EXTPOL.[3:0]) Interrupt acknowledge for all active interrupts serviced by the CPU Active interrupt identification number • Valid during IACK for all active interrupts (not just external) • Encoding order follows the interrupt-service fetch-packet ordering LITTLE ENDIAN/BIG ENDIAN LENDIAN H3 I Migh, LENDIAN selects little-endian byte/half-word addressing order within a word if low, LENDIAN selects big-endian addressing	EMU1	Y1	I/O/Z	Emulation pin 1, pullup with a dedicated 20-kΩ resistor [¶]				
RESET K2 I Device reset NMI L2 I Nonmaskable interrupt • Edge-driven (rising edge) EXT_INT7 U3 EXT_INT6 V2 EXT_INT5 W1 • Edge-driven • Polarity independently selected via the external interrupt polarity register bits (EXTPOL.[3:0]) IACK Y2 O Interrupt acknowledge for all active interrupts serviced by the CPU INUM3 AA1 INUM2 W4 INUM1 AA2 INUM0 AB1 I I High, LENDIAN/BIG ENDIAN LENDIAN H3 I I If high, LENDIAN selects little-endian byte/half-word addressing order within a word lif low, LENDIAN selects big-endian addressing POWER-DOWN STATUS	EMU0	W3	I/O/Z	Emulation pin 0, pullup with a dedicated 20-kΩ resistor [¶]				
NMI L2 I Nonmaskable interrupt • Edge-driven (rising edge) EXT_INT7 U3 EXT_INT6 V2 EXT_INT5 W1 Polarity independently selected via the external interrupt polarity register bits (EXTPOL.[3:0]) IACK Y2 O Interrupt acknowledge for all active interrupts serviced by the CPU INUM3 AA1 INUM2 W4 INUM1 AA2 INUM0 AB1 I High, LENDIAN/BIG ENDIAN LENDIAN H3 I If high, LENDIAN selects big-endian addressing POWER-DOWN STATUS		•		RESET AND INTERRUPTS				
POWER-DOWN STATUS EXT_INT0 EXT_INT7 U3 EXT_INT6 EXT_INT5 EXT_INT5 W1 External interrupts Polarity independently selected via the external interrupt polarity register bits (EXTPOL.[3:0]) Interrupt acknowledge for all active interrupts serviced by the CPU Active interrupt identification number Valid during IACK for all active interrupts (not just external) Encoding order follows the interrupt-service fetch-packet ordering LITTLE ENDIAN/BIG ENDIAN LENDIAN H3 I If high, LENDIAN selects little-endian byte/half-word addressing order within a word If low, LENDIAN selects big-endian addressing POWER-DOWN STATUS	RESET	K2	I	Device reset				
EXT_INT6	NMI	L2	I	· '				
EXT_INT6	EXT_INT7	U3		E-ternal intermedia				
Polarity independently selected via the external interrupt polarity register bits (EXTPOL.[3:0]) IACK Y2 O Interrupt acknowledge for all active interrupts serviced by the CPU INUM3 AA1 INUM2 W4 INUM1 AA2 INUM0 AB1 Consider the external interrupt polarity register bits (EXTPOL.[3:0]) Active interrupt acknowledge for all active interrupts serviced by the CPU Active interrupt identification number • Valid during IACK for all active interrupts (not just external) • Encoding order follows the interrupt-service fetch-packet ordering LITTLE ENDIAN/BIG ENDIAN LENDIAN H3 I If high, LENDIAN selects little-endian byte/half-word addressing order within a word If low, LENDIAN selects big-endian addressing POWER-DOWN STATUS	EXT_INT6	V2	1	· • • • • • • • • • • • • • • • • • • •				
IACK Y2 O Interrupt acknowledge for all active interrupts serviced by the CPU INUM3 INUM2 INUM1 INUM2 INUM1 INUM0 AB1 Active interrupt identification number • Valid during IACK for all active interrupts (not just external) • Encoding order follows the interrupt-service fetch-packet ordering LITTLE ENDIAN/BIG ENDIAN LENDIAN I I fligh, LENDIAN selects little-endian byte/half-word addressing order within a word If low, LENDIAN selects big-endian addressing POWER-DOWN STATUS	EXT_INT5	W1	1 '	Polarity independently selected via the external interrupt polarity register bits				
INUM3 AA1 INUM2 W4 INUM1 AA2 INUM0 AB1 LITTLE ENDIAN/BIG ENDIAN LENDIAN H3 I I I I I I I I I I I I I I I I I I	EXT_INT4	U4	1	(EXTPOL.[3:0])				
Active interrupt identification number Valid during IACK for all active interrupts (not just external) Encoding order follows the interrupt-service fetch-packet ordering LITTLE ENDIAN/BIG ENDIAN LENDIAN H3 I I fligh, LENDIAN selects little-endian byte/half-word addressing order within a word If low, LENDIAN selects big-endian addressing POWER-DOWN STATUS		Y2	0	Interrupt acknowledge for all active interrupts serviced by the CPU				
Valid during IACK for all active interrupts (not just external) Encoding order follows the interrupt-service fetch-packet ordering LITTLE ENDIAN/BIG ENDIAN LENDIAN H3 I I fligh, LENDIAN selects little-endian byte/half-word addressing order within a word If low, LENDIAN selects big-endian addressing POWER-DOWN STATUS	INUM3	AA1						
INUM1 AA2 INUM0 AB1 • Encoding order follows the interrupt-service fetch-packet ordering LITTLE ENDIAN/BIG ENDIAN LENDIAN H3 I I I I I I I I I I I I I I I I I I	INUM2	W4	1					
INUMO AB1 LITTLE ENDIAN/BIG ENDIAN LENDIAN H3 I I If high, LENDIAN selects little-endian byte/half-word addressing order within a word If low, LENDIAN selects big-endian addressing POWER-DOWN STATUS	INUM1	AA2	0	, , , ,				
LENDIAN H3 I If high, LENDIAN selects little-endian byte/half-word addressing order within a word If low, LENDIAN selects big-endian addressing POWER-DOWN STATUS	INUM0	AB1		Enoughing order removes the interrupt service reterr-packet ordering				
If low, LENDIAN selects big-endian addressing POWER-DOWN STATUS				LITTLE ENDIAN/BIG ENDIAN				
POWER-DOWN STATUS	LENDIAN	НЗ	I	, , ,				
	PD	D3	0	Power-down mode 2 or 3 (active if high)				

[†] I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground

[¶] For emulation and normal operation, pull up EMU1 and EMU0 with a dedicated 20-k Ω resistor. For boundary scan, pull down EMU1 and EMU0 with a dedicated 20-k Ω resistor.



[‡] PLLV and PLLG are not part of external voltage supply or ground. See the *clock PLL* section for information on how to connect these pins.

[§] A = Analog Signal (PLL Filter)

SIGNAL	PIN NO.	TYPE†					
NAME	GJC		DESCRIPTION				
	HOST-PORT INTERFACE (HPI)						
HINT	H26	0	Host interrupt (from DSP to host)				
HCNTL1	F23	I	Host control - selects between control, address, or data registers				
HCNTL0	D25	I	Host control - selects between control, address, or data registers				
HHWIL	C26	I	Host half-word select - first or second half-word (not necessarily high or low order)				
HBE1	E23	I	Host byte select within word or half-word				
HBE0	D24	I	Host byte select within word or half-word				
HR/₩	C23	I	Host read or write select				
HD15	B13						
HD14	B14						
HD13	C14						
HD12	B15						
HD11	D15						
HD10	B16						
HD9	A17						
HD8	B17	1/0/7	Heat part data (wood for transfer of data, address, and control)				
HD7	D16	I/O/Z	Host-port data (used for transfer of data, address, and control)				
HD6	B18						
HD5	A19						
HD4	C18						
HD3	B19						
HD2	C19						
HD1	B20						
HD0	B21						
HAS	C22	1	Host address strobe				
HCS	B23	-	Host chip select				
HDS1	D22	1	Host data strobe 1				
HDS2	A24	1	Host data strobe 2				
HRDY	J24	0	Host ready (from DSP to host)				
			BOOT MODE				
BOOTMODE4	D8						
BOOTMODE3	B4	ı					
BOOTMODE2	A3		Boot mode				
BOOTMODE1	D5						
BOOTMODE0	C4						

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SIGNAL	PIN NO.		PERCENTION					
NAME	GJC	TYPE†	DESCRIPTION					
	EMIF - CONTROL SIGNALS COMMON TO ALL TYPES OF MEMORY							
CE3	AE22							
CE2	AD26	0/7	Memory space enables					
CE1	AB24	O/Z	 Enabled by bits 24 and 25 of the word address Only one asserted during any external data access 					
CE0	AC26]	, , , , , , , , , , , , , , , , , , , ,					
BE3	AB25		Byte-enable control					
BE2	AA24]	Decoded from the two lowest bits of the internal address					
BE1	Y23	O/Z	Byte-write enables for most types of memory					
BE0	AA26	1	Can be directly connected to SDRAM read and write mask signal (SDQM)					
			EMIF - ADDRESS					
EA21	J26							
EA20	K25	1						
EA19	L24	1						
EA18	K26	1						
EA17	M26	1						
EA16	M25	1						
EA15	P25	1						
EA14	P24							
EA13	R25	1						
EA12	T26]						
EA11	R23	O/Z	External address (word address)					
EA10	U26	1						
EA9	U25	1						
EA8	T23							
EA7	V26]						
EA6	V25	1						
EA5	W26]						
EA4	V24	1						
EA3	W25	1						
EA2	Y26]						

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SIGNAL	PIN NO.		
NAME	GJC	TYPE†	DESCRIPTION
			EMIF - DATA
ED31	AB2		
ED30	AC1		
ED29	AA4	1	
ED28	AD1	1	
ED27	AC3	1	
ED26	AD4	1	
ED25	AF3	1	
ED24	AE4	1	
ED23	AD5		
ED22	AF4		
ED21	AE5]	
ED20	AD6]	
ED19	AE6]	
ED18	AD7		
ED17	AC8		
ED16	AF7	1/0/7	Futurnal data
ED15	AD9	I/O/Z	External data
ED14	AD10		
ED13	AF9		
ED12	AC11		
ED11	AE10]	
ED10	AE11]	
ED9	AF11]	
ED8	AE14		
ED7	AF15]	
ED6	AE15	1	
ED5	AF16	1	
ED4	AC15	1	
ED3	AE17	1	
ED2	AF18	1	
ED1	AF19		
ED0	AC17		
	i	1	EMIF - ASYNCHRONOUS MEMORY CONTROL
ARE	Y24	O/Z	Asynchronous memory read enable
AOE	AC24	O/Z	Asynchronous memory output enable
ĀWĒ	AD23	O/Z	Asynchronous memory write enable
ARDY	W23	I	Asynchronous memory ready input

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SIGNAL	PIN NO.					
NAME	GJC	TYPE	DESCRIPTION			
	EMIF - SYNCHRONOUS BURST SRAM (SBSRAM) CONTROL					
SSADS	AC20	O/Z	SBSRAM address strobe			
SSOE	AF21	O/Z	SBSRAM output enable			
SSWE	AD19	O/Z	SBSRAM write enable			
SSCLK	AD17	0	SBSRAM clock			
			EMIF - SYNCHRONOUS DRAM (SDRAM) CONTROL			
SDA10	AD21	O/Z	SDRAM address 10 (separate for deactivate command)			
SDRAS	AF24	O/Z	SDRAM row-address strobe			
SDCAS	AD22	O/Z	SDRAM column-address strobe			
SDWE	AF23	O/Z	SDRAM write enable			
SDCLK	AE20	0	SDRAM clock			
			EMIF - BUS ARBITRATION			
HOLD	AA25	I	Hold request from the host			
HOLDA	A7	0	Hold-request acknowledge to the host			
			TIMER1			
TOUT1	H24	0	Timer 1 or general-purpose output			
TINP1	K24	I	Timer 1 or general-purpose input			
			TIMERO			
TOUT0	M4	0	Timer 0 or general-purpose output			
TINP0	K4	I	Timer 0 or general-purpose input			
			DMA ACTION COMPLETE STATUS			
DMAC3	D2					
DMAC2	F4] _	DMA selfere as models			
DMAC1	D1	0	DMA action complete			
DMAC0	E2]				
		М	ULTICHANNEL BUFFERED SERIAL PORT 1 (McBSP1)			
CLKS1	E25	I	External clock source (as opposed to internal)			
CLKR1	H23	I/O/Z	Receive clock			
CLKX1	F26	I/O/Z	Transmit clock			
DR1	D26	I	Receive data			
DX1	G23	O/Z	Transmit data			
FSR1	E26	I/O/Z	Receive frame sync			
FSX1	F25	I/O/Z	Transmit frame sync			

FSX1 F25 I/O/Z Transmit frame sync

† I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground

SIGNAL	PIN NO.		PERCENTAGE
NAME	GJC	TYPE†	DESCRIPTION
	_	М	ULTICHANNEL BUFFERED SERIAL PORT 0 (McBSP0)
CLKS0	L4	I	External clock source (as opposed to internal)
CLKR0	M2	I/O/Z	Receive clock
CLKX0	L1	I/O/Z	Transmit clock
DR0	J1	I	Receive data
DX0	R1	O/Z	Transmit data
FSR0	P4	I/O/Z	Receive frame sync
FSX0	P3	I/O/Z	Transmit frame sync
			RESERVED FOR TEST
RSV0	T2	I	Reserved for testing, pullup with a dedicated 20-k Ω resistor
RSV1	G2	I	Reserved for testing, pullup with a dedicated 20-kΩ resistor
RSV2	C11	I	Reserved for testing, pullup with a dedicated 20-kΩ resistor
RSV3	B9	I	Reserved for testing, pullup with a dedicated 20-k Ω resistor
RSV4	A6	I	Reserved for testing, <i>pulldown</i> with a dedicated 20-kΩ resistor
RSV5	C8	0	Reserved (leave unconnected, <i>do not</i> connect to power or ground)
RSV6	C21	I	Reserved for testing, pullup with a dedicated 20-k Ω resistor
RSV7	B22	I	Reserved for testing, pullup with a dedicated 20-k Ω resistor
RSV8	A23	I	Reserved for testing, pullup with a dedicated 20-k Ω resistor
RSV9	E4	0	Reserved (leave unconnected, <i>do not</i> connect to power or ground)
			UNCONNECTED PINS
	A8		
	B8		
	C9		
	D10		
	D21		
NC	G1		Unconnected pins
	H1		
	H2		
	J2]	
	КЗ]	
	R2		

[†] I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground

SIGNAL	PIN NO.	TYPE†	DESCRIPTION
NAME	GJC	ITPE	DESCRIPTION
	•		3.3-V SUPPLY VOLTAGE PINS
	A10		
	A15		
	A18		
	A21		
	A22		
	B7		
	C1		
	D17		
	F3		
	G24		
	G25		
	H25		
	J25		
	L25	1	
	МЗ		
	N3		
	N23		
	R26		
	T24		
DV_DD	U24	s	3.3-V supply voltage
D V DD	W24]	o.o v oupply voltage
	Y4		
	AB3		
	AB4		
	AB26		
	AC6		
	AC10		
	AC19		
	AC21		
	AC22		
	AC25		
	AD11		
	AD13		
	AD15		
	AD18		
	AE18		
	AE21		
	AF5		
	AF6		
	AF17		

[†] I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground



CICNAL	PIN NO.		Signal Descriptions (Continued)
SIGNAL NAME	GJC	TYPE†	DESCRIPTION
	1.00		1.8-V SUPPLY VOLTAGE PINS
	A5		
	A12		
	A16		
	A20		
	B2		
	В6		
	B11		
	B12		
	B25		
	СЗ		
	C15		
	C20		
	C24		
	D4		
	D6		
	D7		
	D9		
	D14		
CV _{DD}	D18	s	1.8-V supply voltage
- 100	D20		
	D23		
	E1		
	F1		
	H4 J4		
	J23		
	K1		
	K23		
	M1		
	M24		
	N4		
	N25		
	P2		
	P23		
	Т3	1 !	
	T4		
	U1		
	V4	V4	

[†] I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground



SIGNAL	PIN NO.	T/D=+	DECORPTION				
NAME	GJC	TYPE†	DESCRIPTION				
	1.8-V SUPPLY VOLTAGE PINS (CONTINUED)						
	V23						
,	AC4						
	AC9						
	AC12						
	AC13						
	AC18						
	AC23						
	AD3						
CV _{DD}	AD8	S	1.8-V supply voltage				
000	AD14		The Couppy Vollage				
	AD24						
	AE2						
.	AE8						
	AE12						
	AE25						
	AF12						
	-						
	-						
		1	GROUND PINS				
-	A1						
-	A2						
	A4						
-	A13						
-	A14						
	A25						
	A26						
	B1						
]	B3	ONE					
V _{SS}	B5	GND	Ground pins				
	B24						
	B26						
	C2 C7						
	C/ C13						
	C13						
	C16						
	C17						
	020						

[†] I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground



SIGNAL	PIN NO.	T/DE‡	DESCRIPTION OF THE PROPERTY OF				
NAME	GJC	TYPE†	DESCRIPTION				
	GROUND PINS (CONTINUED)						
	D19]					
	E3]					
	E24						
	F2						
	F24						
	G3						
	G4						
	G26						
	J3						
	L23]					
	L26]					
	M23]					
	N1						
	N2						
	N24						
	N26						
	P1						
	P26						
	R24	CND	Cround sine				
V_{SS}	T25	GND	Ground pins				
	U2						
	U23						
	V1						
	V3						
	Y3]					
	Y25]					
	AA3]					
	AA23]					
	AB23]					
	AC2						
	AC5]					
	AC7						
	AC14]					
	AC16]					
	AD2]					
	AD12]					
	AD16						
	AD20						

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SM320C6201-EP FIXED-POINT DIGITAL SIGNAL PROCESSOR

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SIGNAL	PIN NO.							
NAME	GJC	TYPE†	DESCRIPTION					
	GROUND PINS (CONTINUED)							
	AD25							
	AE1							
	AE3							
	AE7							
	AE9							
	AE13							
	AE16							
	AE19							
	AE23							
V_{SS}	AE24	GND	Ground pins					
	AE26							
	AF1	1						
	AF2							
	AF8							
	AF10							
	AF13	4 5						
	AF14							
	AF25							
	AF26							

[†] I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground

SM320C6201-EP FIXED-POINT DIGITAL SIGNAL PROCESSOR

SGUS041A - MAY 2003 - REVISED JANUARY 2004

development support

TI offers an extensive line of development tools for the TMS320C6000™ DSP platform, including tools to evaluate the performance of the processors, generate code, develop algorithm implementations, and fully integrate and debug software and hardware modules.

The following products support development of C6000™ DSP-based applications:

Software Development Tools:

Code Composer Studio™ Integrated Development Environment (IDE) including Editor C/C++/Assembly Code Generation, and Debug plus additional development tools Scalable, Real-Time Foundation Software (DSP BIOS), which provides the basic run-time target software needed to support any DSP application.

Hardware Development Tools:

Extended Development System (XDS[™]) Emulator (supports C6000[™] DSP multiprocessor system debug) EVM (Evaluation Module)

The *TMS320 DSP Development Support Reference Guide* (SPRU011) contains information about development-support products for all TMS320[™] DSP family member devices, including documentation. See this document for further information on TMS320[™] DSP documentation or any TMS320[™] DSP support products from Texas Instruments. An additional document, the *TMS320 Third-Party Support Reference Guide* (SPRU052), contains information about TMS320[™] DSP-related products from other companies in the industry. To receive TMS320[™] DSP literature, contact the Literature Response Center at 800/477-8924.

For a complete listing of development-support tools for the TMS320C6000™ DSP platform, visit the Texas Instruments web site on the Worldwide Web at http://www.ti.com uniform resource locator (URL) and under "Development Tools", select "Digital Signal Processors". For information on pricing and availability, contact the nearest TI field sales office or authorized distributor.

Code Composer Studio, XDS, and TMS320 are trademarks of Texas Instruments.



device and development support tool nomenclature

To designate the stages in the product development cycle, TI assigns prefixes to the part numbers of all TMS320™ DSP family devices and support tools. Each TMS320™ DSP member has one of three prefixes: TMX, TMP, or TMS, and each SMJ320™ DSP member has one of three prefixes: SMX, SM, or SMJ. Texas Instruments recommends two of three possible prefix designators for its support tools: TMDX and TMDS. These prefixes represent evolutionary stages of product development from engineering prototypes (TMX/TMDX) through fully qualified production devices/tools (TMS/TMDS). This development flow is defined below.

Device development evolutionary flow:

SMX Experimental device that is not necessarily representative of the final device's electrical

specifications

TMP Final silicon die that conforms to the device's electrical specifications but has not completed

quality and reliability verification

SM/SMJ Fully-qualified production device

Support tool development evolutionary flow:

TMDX Development support product that has not yet completed Texas Instruments internal qualification

testing.

TMDS Fully qualified development support product

TMX and TMP devices and TMDX development support tools are shipped against the following disclaimer:

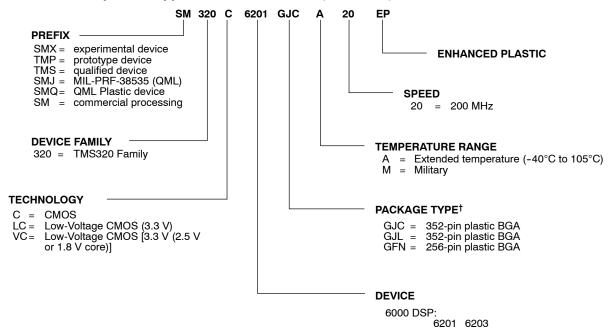
"Developmental product is intended for internal evaluation purposes."

TMS as well as SM/SMJ devices and TMDS development support tools have been characterized fully, and the quality and reliability of the device has been demonstrated fully. TI's standard warranty applies.

Predictions show that prototype devices (TMX or TMP) have a greater failure rate than the standard production devices. Texas Instruments recommends that these devices not be used in any production system because their expected end-use failure rate still is undefined. Only qualified production devices are to be used.

TI device nomenclature also includes a suffix with the device family name. This suffix indicates the package type (for example, GNM) and temperature range (for example, M). Figure 4 provides a legend for reading the complete device name for many TMS320™ DSP family members.

device and development-support tool nomenclature (continued)



NOTE: Not all speed, package, process, and temperature combinations are available.

Figure 4. TMS320C6000™ Device Nomenclature (Including SM320C6201-EP)

6701 6711

MicroStar BGA is a trademark of Texas Instruments.



[†] BGA = Ball Grid Array

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documentation support

Extensive documentation supports all TMS320™ DSP family devices from product announcement through applications development. The types of documentation available include: data sheets, such as this document, with design specifications; complete user's reference guides for all devices and tools; technical briefs; development-support tools; on-line help; and hardware and software applications. The following is a brief, descriptive list of support documentation specific to the C6000™ DSP devices:

The *TMS320C6000 CPU and Instruction Set Reference Guide* (literature number SPRU189) describes the C6000 CPU (DSP core) architecture, instruction set, pipeline, and associated interrupts.

The *TMS320C6000 Peripherals Reference Guide* (literature number SPRU190) describes the functionality of the peripherals available on the C6000[™] DSP platform of devices, such as the 64-/32-/16-bit external memory interfaces (EMIFs), 32-/16-bit host-port interfaces (HPIs), multichannel buffered serial ports (McBSPs), direct memory access (DMA), enhanced direct-memory-access (EDMA) controller, expansion bus (XB), peripheral component interconnect (PCI), clocking and phase-locked loop (PLL); and power-down modes. This guide also includes information on internal data and program memories.

The *TMS320C6000 Technical Brief* (literature number SPRU197) gives an introduction to the C62x[™]/C67x[™] devices, associated development tools, and third-party support.

The tools support documentation is electronically available within the Code Composer Studio™ IDE. For a complete listing of the latest C6000™ DSP documentation, visit the Texas Instruments web site on the Worldwide Web at http://www.ti.com uniform resource locator (URL).

C67x is a trademark of Texas Instruments.

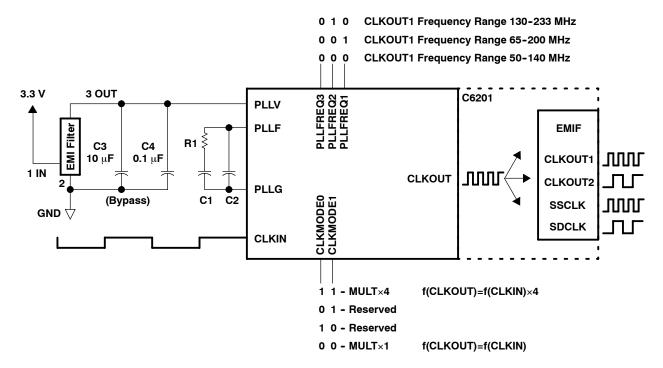


clock PLL

All of the C62x[™] clocks are generated from a single source through the CLKIN pin. This source clock either drives the PLL, which generates the internal CPU clock, or bypasses the PLL to become the CPU clock.

To use the PLL to generate the CPU clock, the filter circuit shown in Figure 5 must be properly designed. Note that for C6201, the EMI filter must be powered by the I/O voltage (3.3 V).

To configure the C62x[™] PLL clock for proper operation, see Figure 5 and Table 2. To minimize the clock jitter, a single clean power supply should power both the C62x[™] DSP device and the external clock oscillator circuit. The minimum CLKIN rise and fall times should also be observed. See the *input and output clocks* section for input clock timing requirements.



- NOTES: A. Keep the lead length and the number of vias between pin PLLF, pin PLLG, R1, C1, and C2 to a minimum. In addition, place all PLL components (R1, C1, C2, C3, C4, and EMI Filter) as close to the C6000[™] DSP device as possible. Best performance is achieved with the PLL components on a single side of the board without jumpers, switches, or components other than the ones shown. For CLKMODE x4, values for C1, C2, and R1 are fixed and apply to all valid frequency ranges of CLKIN and CLKOUT.
 - B. For CLKMODE x1, the PLL is bypassed and all six external PLL components can be removed. For this case, the PLLV terminal has to be connected to a clean supply and the PLLG and PLLF terminals should be tied together.
 - C. Due to overlap of frequency ranges when choosing the PLLFREQ, more than one frequency range can contain the CLKOUT1 frequency. Choose the lowest frequency range that includes the desired frequency. For example, for CLKOUT1 = 133 MHz, a PLLFREQ value of 000b should be used. For CLKOUT1 = 200 MHz, PLLFREQ should be set to 001b. PLLFREQ values other than 000b, 001b, and 010b are reserved.
 - D. The 3.3-V supply for the EMI filter (and PLLV) must be from the same 3.3-V power plane supplying the I/O voltage, DV_{DD}.
 - E. EMI filter manufacturer TDK part number ACF451832-153-T

Figure 5. PLL Block Diagram



clock PLL (continued)

Table 2. PLL Component Selection Table

CLKMODE	CLKIN RANGE (MHz)	CPU CLOCK FREQUENCY (CLKOUT1) RANGE (MHz)	CLKOUT2 RANGE (MHz)	R1 (Ω)	C1 (nF)	C2 (pF)	TYPICAL LOCK TIME (μs) [†]
x4	12.5-50	50-200	25-100	60.4	27	560	75

[†] Under some operating conditions, the maximum PLL lock time may vary as much as 150% from the specified typical value. For example, if the typical lock time is specified as 100 µs, the maximum value may be as long as 250 µs.

power-supply sequencing

TI DSPs do not require specific power sequencing between the core supply and the I/O supply. However, systems should be designed to ensure that neither supply is powered up for extended periods of time if the other supply is below the proper operating voltage.

system-level design considerations

System-level design considerations, such as bus contention, may require supply sequencing to be implemented. In this case, the core supply should be powered up at the same time as, or prior to (and powered down after), the I/O buffers. This is to ensure that the I/O buffers receive valid inputs from the core before the output buffers are powered up, thus, preventing bus contention with other chips on the board.

power-supply design considerations

For systems using the C6000™ DSP platform of devices, the core supply may be required to provide in excess of 2 A per DSP until the I/O supply is powered up. This extra current condition is a result of uninitialized logic within the DSP(s) and is corrected once the CPU sees an internal clock pulse. With the PLL enabled, as the I/O supply is powered on, a clock pulse is produced stopping the extra current draw from the supply. With the PLL disabled, an external clock pulse may be required to stop this extra current draw. A normal current state returns once the I/O power supply is turned on and the CPU sees a clock pulse. Decreasing the amount of time between the core supply power up and the I/O supply power up can minimize the effects of this current draw.

A dual-power supply with simultaneous sequencing, such as available with TPS563xx controllers or PT69xx plug-in power modules, can be used to eliminate the delay between core and I/O power up [see the *Using the TPS56300 to Power DSPs* application report (literature number SLVA088)]. A Schottky diode can also be used to tie the core rail to the I/O rail, effectively pulling up the I/O power supply to a level that can help initialize the logic within the DSP.

Core and I/O supply voltage regulators should be located close to the DSP (or DSP array) to minimize inductance and resistance in the power delivery path. Additionally, when designing for high-performance applications utilizing the $C6000^{TM}$ platform of DSPs, the PC board should include separate power planes for core, I/O, and ground, all bypassed with high-quality low-ESL/ESR capacitors.

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absolute maximum ratings over operating case temperature ranges (unless otherwise noted)[†]

Supply voltage range, CV _{DD} (see Note 1)	0.3 V to 2.3 V
Supply voltage range, DV _{DD} (see Note 1)	0.3 V to 4 V
Input voltage range	0.3 V to 4 V
Output voltage range	0.3 V to 4 V
Operating case temperature ranges T _C : (A version)	40°C to 105°C
Storage temperature range, T _{sto}	65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			MIN	NOM	MAX	UNIT
CV_{DD}	Supply voltage		1.71	1.8	1.89	V
DV_DD	Supply voltage		3.14	3.30	3.46	V
V_{SS}	Supply ground		0	0	0	V
V_{IH}	High-level input voltage		2			V
V_{IL}	Low-level input voltage				8.0	V
I _{OH}	High-level output current				-12	mA
I _{OL}	Low-level output current				12	mA
T _C	Operating case temperature	A version	-40		105	°C

electrical characteristics over recommended ranges of supply voltage and operating case temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _{OH}	High-level output voltage	DV _{DD} = MIN, I _{OH} = MAX	2.4			V
V _{OL}	Low-level output voltage	$DV_{DD} = MIN,$ $I_{OL} = MAX$			0.6	V
I _I	Input current [‡]	$V_I = V_{SS}$ to DV_{DD}			±10	uA
I _{OZ}	Off-state output current	$V_O = DV_{DD}$ or 0 V			±10	uA
I _{DD2V}	Supply current, CPU + CPU memory access§	CV _{DD} = NOM, CPU clock = 167 MHz		380		mA
I _{DD2V}	Supply current, peripherals§	CV _{DD} = NOM, CPU clock = 167 MHz		240		mA
I _{DD3V}	Supply current, I/O pins§	DV _{DD} = NOM, CPU clock = 167 MHz		90		mA
C _i	Input capacitance				10	pF
C _o	Output capacitance				10	pF

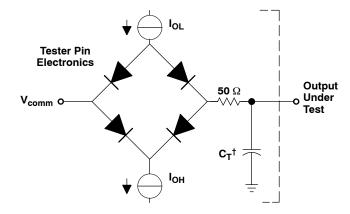
[‡] TMS and TDI are not included due to internal pullups. TRST is not included due to internal pulldown.



NOTE 1: All voltage values are with respect to V_{SS}.

[§] Measured with average activity (50% high / 50% low power). For more details on CPU, peripheral, and I/O activity, see the *TMS320C6000 Power Consumption Summary* application report (literature number SPRA486).

PARAMETER MEASUREMENT INFORMATION



Where: I_{OL} = 2 mA I_{OH} = 2 mA V_{comm} = 0.8 V

C_T = 15-30-pF typical load-circuit capacitance

Figure 6. TTL-Level Outputs

signal transition levels

All input and output timing parameters are referenced to 1.5 V for both "0" and "1" logic levels.

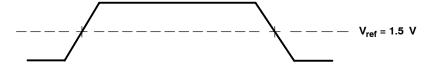


Figure 7. Input and Output Voltage Reference Levels for AC Timing Measurements

All rise and fall transition timing parameters are referenced to V_{IL} MAX and V_{IH} MIN for input clocks, and V_{OL} MAX and V_{OH} MIN for output clocks.

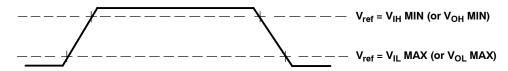


Figure 8. Rise and Fall Transition Time Voltage Reference Levels

[†] Typical distributed load circuit capacitance

INPUT AND OUTPUT CLOCKS

timing requirements for CLKIN^{†‡} (see Figure 9)

				-2	200		
NO.			CLKM = >		CLKMC = x1		UNIT
			MIN	MAX	MIN	MAX	
1	t _{c(CLKIN)}	Cycle time, CLKIN	20		5		ns
2	t _{w(CLKINH)}	Pulse duration, CLKIN high	0.4C		0.45C		ns
3	tw(CLKINL)	Pulse duration, CLKIN low	0.4C		0.45C		ns
4	t _{t(CLKIN)}	Transition time, CLKIN		5		0.6	ns

 $^{^{\}dagger}$ The reference points for the rise and fall transitions are measured at V_{IL} MAX and V_{IH} MIN.

[‡] C = CLKIN cycle time in ns. For example, when CLKIN frequency is 50 MHz, use C = 20 ns.

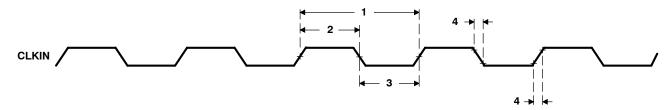


Figure 9. CLKIN Timing Diagram

switching characteristics over recommended operating conditions for CLKOUT1^{§¶#} (see Figure 10)

				-20	00		
NO.		PARAMETER	CLKMO	DE = x4	CLKMOD	E = x1	UNIT
			MIN	MAX	MIN	MAX	
1	t _{c(CKO1)}	Cycle time, CLKOUT1	P - 0.7	P + 0.7	P - 0.7	P + 0.7	ns
2	t _{w(CKO1H)}	Pulse duration, CLKOUT1 high	(P/2) - 0.5	(P/2) + 0.5	PH - 0.5	PH + 0.5	ns
3	t _{w(CKO1L)}	Pulse duration, CLKOUT1 low	(P/2) - 0.5	(P/2) + 0.5	PL - 0.5	PL + 0.5	ns
4	t _{t(CKO1)}	Transition time, CLKOUT1		0.6		0.6	ns

P = 1/CPU clock frequency in ns.

[#] PH is the high period of CLKIN in ns and PL is the low period of CLKIN in ns.

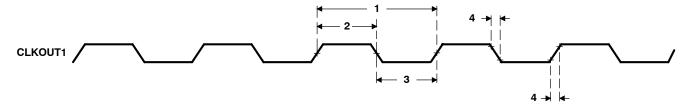


Figure 10. CLKOUT1 Timing Diagram

 $[\]P$ The reference points for the rise and fall transitions are measured at V_{OL} MAX and V_{OH} MIN.

INPUT AND OUTPUT CLOCKS (CONTINUED)

switching characteristics over recommended operating conditions for CLKOUT2^{†‡} (see Figure 11)

NO	DADAMETED	-20	0	
NO.	PARAMETER	MIN	MAX	UNIT
1	$t_{c(CKO2)}$ Cycle time, CLKOUT2	2P - 0.7	2P + 0.7	ns
2	t _{w(CKO2H)} Pulse duration, CLKOUT2 high	P - 0.7	P + 0.7	ns
3	t _{w(CKO2L)} Pulse duration, CLKOUT2 low	P - 0.7	P + 0.7	ns
4	t _{t(CKO2)} Transition time, CLKOUT2		0.6	ns

[†] P = 1/CPU clock frequency in ns.

 $^{^{\}ddagger}$ The reference points for the rise and fall transitions are measured at V_{OL} MAX and V_{OH} MIN.

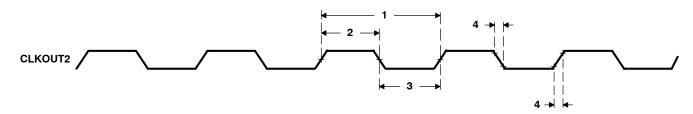


Figure 11. CLKOUT2 Timings

SDCLK, SSCLK timing parameters

SDCLK timing parameters are the same as CLKOUT2 parameters.

SSCLK timing parameters are the same as CLKOUT1 or CLKOUT2 parameters, depending on SSCLK configuration.

switching characteristics over recommended operating conditions for the relation of SSCLK, SDCLK, and CLKOUT2 to CLKOUT1 (see Figure 12)[†]

		PARAMETER	-2	00	
NO.		MIN	MAX	UNIT	
1	t _{d(CKO1-SSCLK)}	Delay time, CLKOUT1 edge to SSCLK edge	(P/2) + 0.2	(P/2) + 4.2	ns
2	t _d (CKO1-SSCLK1/2)	Delay time, CLKOUT1 edge to SSCLK edge (1/2 clock rate)	(P/2) - 1	(P/2) + 2.4	ns
3	t _{d(CKO1-CKO2)}	Delay time, CLKOUT1 edge to CLKOUT2 edge	(P/2) - 1	(P/2) + 2.4	ns
4	t _d (CKO1-SDCLK)	Delay time, CLKOUT1 edge to SDCLK edge	(P/2) - 1	(P/2) + 2.4	ns

[†] P = 1/CPU clock frequency in ns.

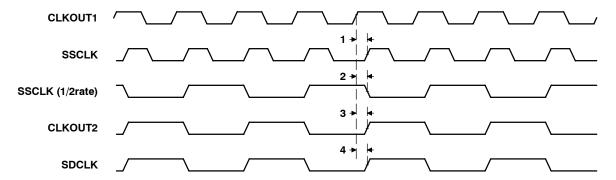


Figure 12. Relation of CLKOUT2, SDCLK, and SSCLK to CLKOUT1



ASYNCHRONOUS MEMORY TIMING

timing requirements for asynchronous memory cycles[†] (see Figure 13 and Figure 14)

NO			-20	00	
NO.			MIN	MAX	UNIT
6	t _{su(EDV-CKO1H)}	Setup time, read EDx valid before CLKOUT1 high	4		ns
7	t _{h(CKO1H-EDV)}	Hold time, read EDx valid after CLKOUT1 high	0.8		ns
10	t _{su(ARDY-CKO1H)}	Setup time, ARDY valid before CLKOUT1 high	3		ns
11	t _{h(CKO1H-ARDY)}	Hold time, ARDY valid after CLKOUT1 high	1.8		ns

[†] To ensure data setup time, simply program the strobe width wide enough. ARDY is internally synchronized. If ARDY does meet setup or hold time, it may be recognized in the current cycle or the next cycle. Thus, ARDY can be an asynchronous input.

switching characteristics over recommended operating conditions for asynchronous memory cycles[‡] (see Figure 13 and Figure 14)

		2424455	-20	00	
NO.		PARAMETER	MIN	MAX	UNIT
1	t _{d(CKO1H-CEV)}	Delay time, CLKOUT1 high to CEx valid	-0.2	4	ns
2	t _{d(CKO1H-BEV)}	Delay time, CLKOUT1 high to BEx valid		4	ns
3	t _d (CKO1H-BEIV)	Delay time, CLKOUT1 high to BEx invalid	-0.2		ns
4	t _d (CKO1H-EAV)	Delay time, CLKOUT1 high to EAx valid		4	ns
5	t _{d(CKO1H-EAIV)}	Delay time, CLKOUT1 high to EAx invalid	-0.2		ns
8	t _{d(CKO1H-AOEV)}	Delay time, CLKOUT1 high to AOE valid	-0.2	4	ns
9	t _{d(CKO1H-AREV)}	Delay time, CLKOUT1 high to ARE valid	-0.2	4	ns
12	t _{d(CKO1H-EDV)}	Delay time, CLKOUT1 high to EDx valid		4	ns
13	t _{d(CKO1H-EDIV)}	Delay time, CLKOUT1 high to EDx invalid	-0.2		ns
14	t _{d(CKO1H-AWEV)}	Delay time, CLKOUT1 high to AWE valid	-0.2	4	ns

[‡] The minimum delay is also the minimum output hold after CLKOUT1 high.

ASYNCHRONOUS MEMORY TIMING (CONTINUED)

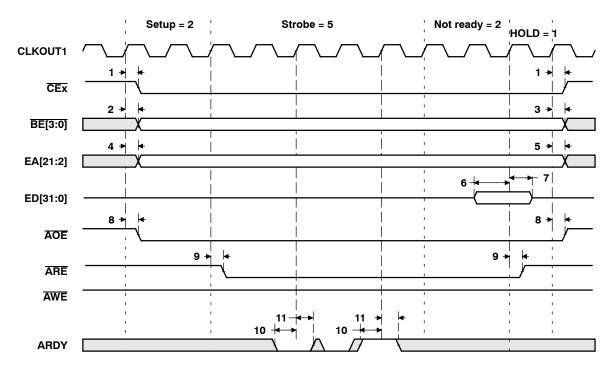


Figure 13. Asynchronous Memory Read Timing

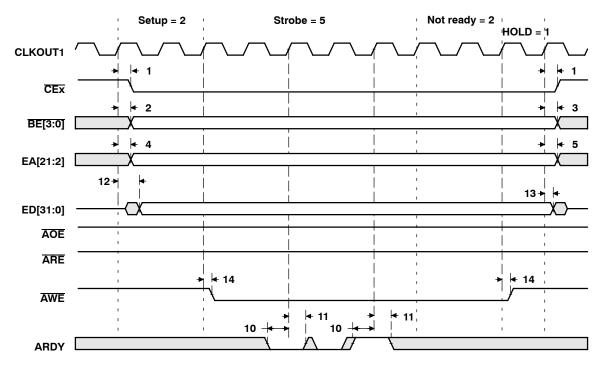


Figure 14. Asynchronous Memory Write Timing

SYNCHRONOUS-BURST MEMORY TIMING

timing requirements for synchronous-burst SRAM cycles (full-rate SSCLK) (see Figure 15)

		-20	00	LINUT
NO.		MIN	MIN MAX	UNIT
7	t _{su(EDV-SSCLKH)} Setup time, read EDx valid before SSCLK high	1.5		ns
8	t _{h(SSCLKH-EDV)} Hold time, read EDx valid after SSCLK high	1.5		ns

switching characteristics over recommended operating conditions for synchronous-burst SRAM cycles[†] (full-rate SSCLK) (see Figure 15 and Figure 16)

		24244555	-200	UNIT
NO.		PARAMETER		
1	t _{osu(CEV-SSCLKH)}	Output setup time, CEx valid before SSCLK high	0.5P - 1.3	ns
2	t _{oh(SSCLKH-CEV)}	Output hold time, CEx valid after SSCLK high	0.5P - 2.3	ns
3	t _{osu(BEV-SSCLKH)}	Output setup time, BEx valid before SSCLK high	0.5P - 1.3	ns
4	toh(SSCLKH-BEIV)	Output hold time, BEx invalid after SSCLK high	0.5P - 2.3	ns
5	t _{osu(EAV-SSCLKH)}	Output setup time, EAx valid before SSCLK high	0.5P - 1.3	ns
6	toh(SSCLKH-EAIV)	Output hold time, EAx invalid after SSCLK high	0.5P - 2.3	ns
9	t _{osu(ADSV-SSCLKH)}	Output setup time, SSADS valid before SSCLK high	0.5P - 1.3	ns
10	t _{oh(SSCLKH-ADSV)}	Output hold time, SSADS valid after SSCLK high	0.5P - 2.3	ns
11	t _{osu(OEV-SSCLKH)}	Output setup time, SSOE valid before SSCLK high	0.5P - 1.3	ns
12	t _{oh(SSCLKH-OEV)}	Output hold time, SSOE valid after SSCLK high	0.5P - 2.3	ns
13	t _{osu(EDV-SSCLKH)}	Output setup time, EDx valid before SSCLK high	0.5P - 1.3	ns
14	toh(SSCLKH-EDIV)	Output hold time, EDx invalid after SSCLK high	0.5P - 2.3	ns
15	t _{osu(WEV-SSCLKH)}	Output setup time, SSWE valid before SSCLK high	0.5P - 1.3	ns
16	toh(SSCLKH-WEV)	Output hold time, SSWE valid after SSCLK high	0.5P - 2.3	ns

[†] When the PLL is used (CLKMODE x4), P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns. For CLKMODE x1, 0.5P is defined as PH (pulse duration of CLKIN high) for all output setup times; 0.5P is defined as PL (pulse duration of CLKIN low) for all output hold times.

SYNCHRONOUS-BURST MEMORY TIMING (CONTINUED)

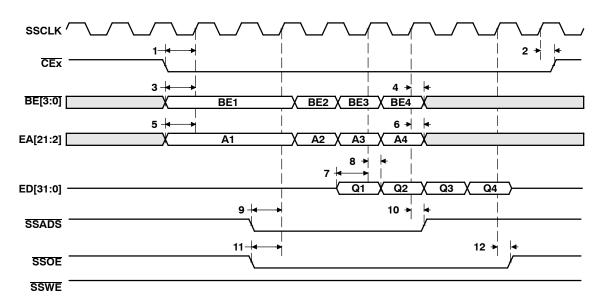


Figure 15. SBSRAM Read Timing (Full-Rate SSCLK)

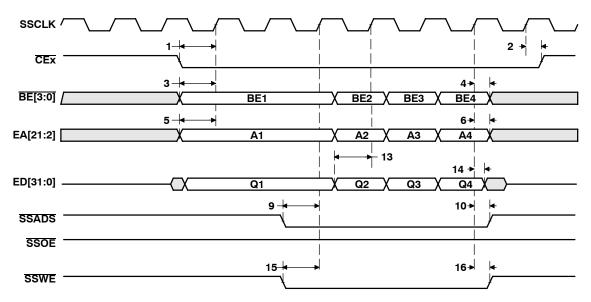


Figure 16. SBSRAM Write Timing (Full-Rate SSCLK)

SYNCHRONOUS-BURST MEMORY TIMING (CONTINUED)

timing requirements for synchronous-burst SRAM cycles (half-rate SSCLK) (see Figure 17)

NO			-200		
NO.		MI	N MA	λX	UNIT
7	t _{su(EDV-SSCLKH)} Setup time, read EDx valid before SSCLK high	2.	5		ns
8	t _{h(SSCLKH-EDV)} Hold time, read EDx valid after SSCLK high	1.	5		ns

switching characteristics over recommended operating conditions for synchronous-burst SRAM cycles[†] (half-rate SSCLK) (see Figure 17 and Figure 18)

NO.	PARAMETER		-200	UNIT
			MIN MAX	
1	t _{osu(CEV-SSCLKH)}	Output setup time, CEx valid before SSCLK high	1.5P - 3	ns
2	t _{oh(SSCLKH-CEV)}	Output hold time, CEx valid after SSCLK high	0.5P - 1.5	ns
3	t _{osu(BEV-SSCLKH)}	Output setup time, BEx valid before SSCLK high	1.5P - 3	ns
4	toh(SSCLKH-BEIV)	Output hold time, BEx invalid after SSCLK high	0.5P - 1.5	ns
5	t _{osu(EAV-SSCLKH)}	Output setup time, EAx valid before SSCLK high	1.5P - 3	ns
6	toh(SSCLKH-EAIV)	Output hold time, EAx invalid after SSCLK high	0.5P - 1.5	ns
9	t _{osu(ADSV-SSCLKH)}	Output setup time, SSADS valid before SSCLK high	1.5P - 3	ns
10	t _{oh(SSCLKH-ADSV)}	Output hold time, SSADS valid after SSCLK high	0.5P - 1.5	ns
11	t _{osu(OEV-SSCLKH)}	Output setup time, SSOE valid before SSCLK high	1.5P - 3	ns
12	t _{oh(SSCLKH-OEV)}	Output hold time, SSOE valid after SSCLK high	0.5P - 1.5	ns
13	t _{osu(EDV-SSCLKH)}	Output setup time, EDx valid before SSCLK high	1.5P - 3	ns
14	toh(SSCLKH-EDIV)	Output hold time, EDx invalid after SSCLK high	0.5P - 1.5	ns
15	t _{osu(WEV-SSCLKH)}	Output setup time, SSWE valid before SSCLK high	1.5P - 3	ns
16	t _{oh(SSCLKH-WEV)}	Output hold time, SSWE valid after SSCLK high	0.5P - 1.5	ns

[†] When the PLL is used (CLKMODE x4), P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns. For CLKMODE x1:

^{1.5}P = P + PH, where P = 1/CPU clock frequency, and PH = pulse duration of CLKIN high.

^{0.5}P = PL, where PL = pulse duration of CLKIN low.

SYNCHRONOUS-BURST MEMORY TIMING (CONTINUED)

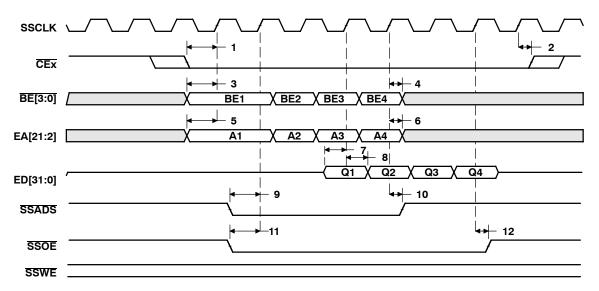


Figure 17. SBSRAM Read Timing (1/2 Rate SSCLK)

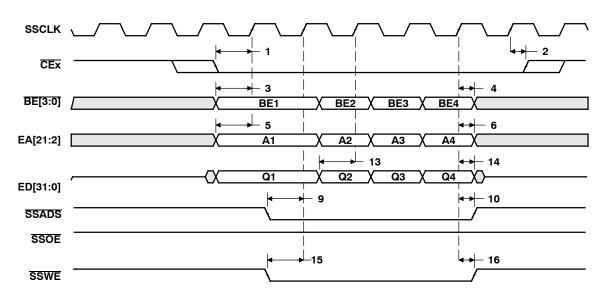


Figure 18. SBSRAM Write Timing (1/2 Rate SSCLK)

SYNCHRONOUS DRAM TIMING

timing requirements for synchronous DRAM cycles (see Figure 19)

NO			-200	
NO.		MIN	MAX	UNIT
7	t _{su(EDV-SDCLKH)} Setup time	read EDx valid before SDCLK high 0.5		ns
8	$t_{h(SDCLKH-EDV)}$ Hold time,	read EDx valid after SDCLK high 3		ns

switching characteristics over recommended operating conditions for synchronous DRAM cycles[†] (see Figure 19-Figure 24)

NO.	PARAMETER		-200	UNIT
			MIN MAX	
1	t _{osu(CEV-SDCLKH)}	Output setup time, CEx valid before SDCLK high	1.5P - 3.5	ns
2	t _{oh(SDCLKH-CEV)}	Output hold time, CEx valid after SDCLK high	0.5P - 1	ns
3	t _{osu(BEV-SDCLKH)}	Output setup time, BEx valid before SDCLK high	1.5P - 3.5	ns
4	t _{oh(SDCLKH-BEIV)}	Output hold time, BEx invalid after SDCLK high	0.5P - 1	ns
5	t _{osu(EAV-SDCLKH)}	Output setup time, EAx valid before SDCLK high	1.5P - 3.5	ns
6	toh(SDCLKH-EAIV)	Output hold time, EAx invalid after SDCLK high	0.5P - 1	ns
9	t _{osu(SDCAS-SDCLKH)}	Output setup time, SDCAS valid before SDCLK high	1.5P - 3.5	ns
10	toh(SDCLKH-SDCAS)	Output hold time, SDCAS valid after SDCLK high	0.5P - 1	ns
11	t _{osu(EDV-SDCLKH)}	Output setup time, EDx valid before SDCLK high	1.5P - 3.5	ns
12	t _{oh(SDCLKH-EDIV)}	Output hold time, EDx invalid after SDCLK high	0.5P - 1	ns
13	t _{osu(SDWE-SDCLKH)}	Output setup time, SDWE valid before SDCLK high	1.5P - 3.5	ns
14	toh(SDCLKH-SDWE)	Output hold time, SDWE valid after SDCLK high	0.5P - 1	ns
15	t _{osu(SDA10V-SDCLKH)}	Output setup time, SDA10 valid before SDCLK high	1.5P - 3.5	ns
16	toh(SDCLKH-SDA10IV)	Output hold time, SDA10 invalid after SDCLK high	0.5P - 1	ns
17	t _{osu(SDRAS-SDCLKH)}	Output setup time, SDRAS valid before SDCLK high	1.5P - 3.5	ns
18	toh(SDCLKH-SDRAS)	Output hold time, SDRAS valid after SDCLK high	0.5P - 1	ns

[†] When the PLL is used (CLKMODE x4), P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns. For CLKMODE x1:

^{1.5}P = P + PH, where P = 1/CPU clock frequency, and PH = pulse duration of CLKIN high.

^{0.5}P = PL, where PL = pulse duration of CLKIN low.

SYNCHRONOUS DRAM TIMING (CONTINUED)

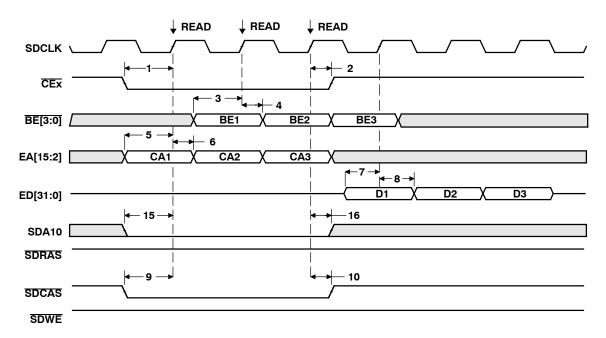


Figure 19. Three SDRAM Read Commands

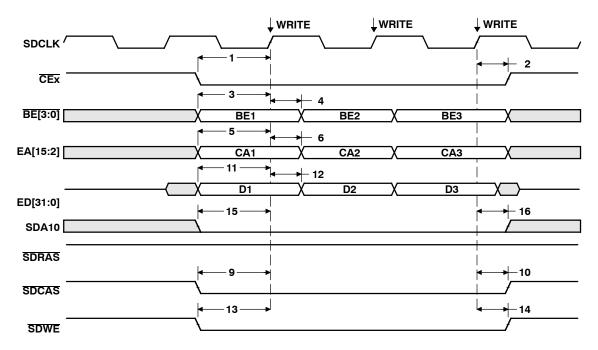


Figure 20. Three SDRAM WRT Commands

SYNCHRONOUS DRAM TIMING (CONTINUED)

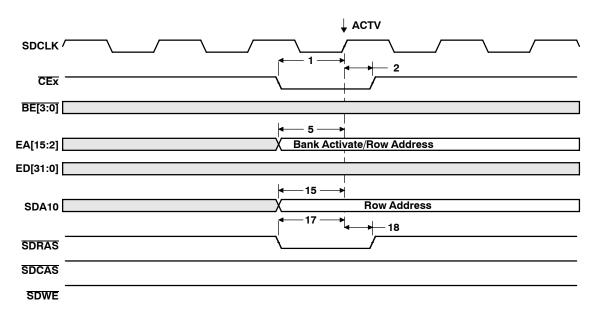


Figure 21. SDRAM ACTV Command

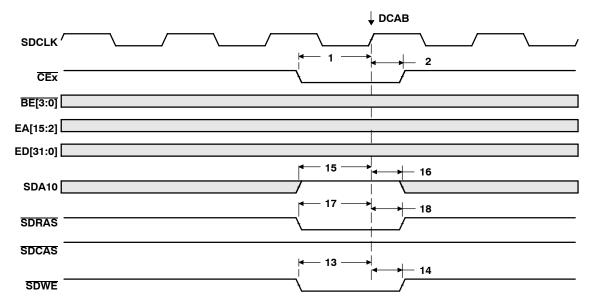


Figure 22. SDRAM DCAB Command

SYNCHRONOUS DRAM TIMING (CONTINUED)

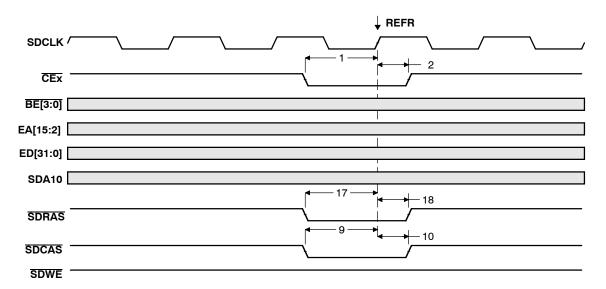


Figure 23. SDRAM REFR Command

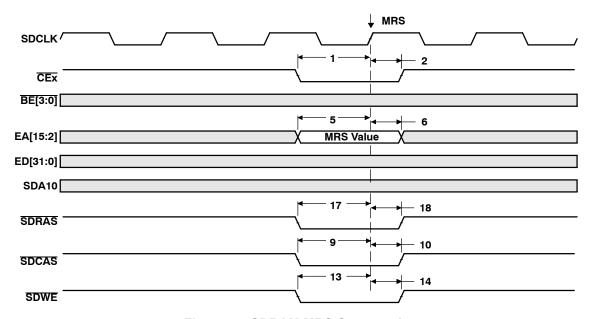


Figure 24. SDRAM MRS Command

HOLD/HOLDA TIMING

timing requirements for the HOLD/HOLDA cycles[†] (see Figure 25)

		-200	
NO.		MIN MAX	UNIT
1	t _{su(HOLDH-CKO1H)} Setup time, HOLD high before CLKOUT1 high	1	ns
2	t _{h(CKO1H-HOLDL)} Hold time, HOLD low after CLKOUT1 high	4	ns

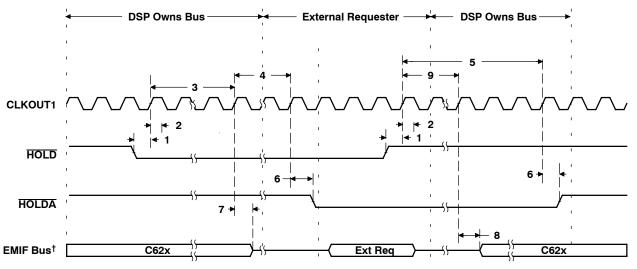
[†] HOLD is synchronized internally. Therefore, if setup and hold times are not met, it will either be recognized in the current cycle or in the next cycle. Thus, HOLD can be an asynchronous input.

switching characteristics over recommended operating conditions for the HOLD/HOLDA cycles[‡] (see Figure 25)

	PARAMETER				
NO.					UNIT
3	t _{d(HOLDL-BHZ)}	Delay time, HOLD low to EMIF Bus high impedance	4P	§	ns
4	t _{d(BHZ-HOLDAL)}	Delay time, EMIF Bus high impedance to HOLDA low	Р	2P	ns
5	t _{d(HOLDH-HOLDAH)}	Delay time, HOLD high to HOLDA high	4P	7P	ns
6	t _d (CKO1H-HOLDAL)	Delay time, CLKOUT1 high to HOLDA valid	1	8	ns
7	t _{d(CKO1H-BHZ)}	Delay time, CLKOUT1 high to EMIF Bus high impedance [¶]	3	11	ns
8	t _{d(CKO1H-BLZ)}	Delay time, CLKOUT1 high to EMIF Bus low impedance [¶]	3	11	ns
9	t _{d(HOLDH-BLZ)}	Delay time, HOLD high to EMIF Bus low impedance	3P	6P	ns

 $^{^{\}ddagger}$ P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

[¶] EMIF Bus consists of CE[3:0], BE[3:0], ED[31:0], EA[21:2], ARE, AOE, AWE, SSADS, SSOE, SSWE, SDA10, SDRAS, SDCAS, and SDWE.



[†] EMIF Bus consists of CE[3:0], BE[3:0], ED[31:0], EA[21:2], ARE, AOE, AWE, SSADS, SSOE, SSWE, SDA10, SDRAS, SDCAS, and SDWE.

Figure 25. HOLD/HOLDA Timing



[§] All pending EMIF transactions are allowed to complete before HOLDA is asserted. The worst cases for this is an asynchronous read or write with external ARDY used or a minimum of eight consecutive SDRAM reads or writes when RBTR8 = 1. If no bus transactions are occurring, then the minimum delay time can be achieved. Also, bus hold can be indefinitely delayed by setting NOHOLD = 1.

RESET TIMING

timing requirements for reset (see Figure 26)

			-20	00	
NO.			MIN	MAX	UNIT
1	t _{w(RST)}	Width of the RESET pulse (PLL stable)†	10		CLKOUT1 cycles
	(,	Width of the RESET pulse (PLL needs to sync up) [‡]	250		μS

[†] This parameter applies to CLKMODE x1 when CLKIN is stable and applies to CLKMODE x4 when CLKIN and PLL are stable.

switching characteristics over recommended operating conditions during reset§¶ (see Figure 26)

		DADAMETED		00	
NO.	PARAMETER		MIN	MAX	UNIT
2	t _{R(RST)}	Response time to change of value in RESET signal	2		CLKOUT1 cycles
3	t _{d(CKO1H-CKO2IV)}	Delay time, CLKOUT1 high to CLKOUT2 invalid	-1		ns
4	t _{d(CKO1H-CKO2V)}	Delay time, CLKOUT1 high to CLKOUT2 valid		10	ns
5	t _d (CKO1H-SDCLKIV)	Delay time, CLKOUT1 high to SDCLK invalid	-1		ns
6	t _d (CKO1H-SDCLKV)	Delay time, CLKOUT1 high to SDCLK valid		10	ns
7	t _d (CKO1H-SSCKIV)	Delay time, CLKOUT1 high to SSCLK invalid	-1		ns
8	t _d (CKO1H-SSCKV)	Delay time, CLKOUT1 high to SSCLK valid		10	ns
9	t _{d(CKO1H-LOWIV)}	Delay time, CLKOUT1 high to low group invalid	-1		ns
10	t _{d(CKO1H-LOWV)}	Delay time, CLKOUT1 high to low group valid		10	ns
11	t _{d(CKO1H-HIGHIV)}	Delay time, CLKOUT1 high to high group invalid	-1		ns
12	t _{d(CKO1H-HIGHV)}	Delay time, CLKOUT1 high to high group valid		10	ns
13	t _{d(CKO1H-ZHZ)}	Delay time, CLKOUT1 high to Z group high impedance	-1		ns
14	t _d (CKO1H-ZV)	Delay time, CLKOUT1 high to Z group valid		10	ns

[§] Low group consists of: IACK, INUM[3:0], DMAC[3:0], PD, TOUT0, and TOUT1

High group consists of:

Z group consists of:

EA[21:2], ED[31:0], CE[3:0], BE[3:0], ARE, AWE, AOE, SSADS, SSOE, SSWE, SDA10, SDRAS, SDCAS, SDWE, HD[15:0], CLKX0, CLKX1, FSX0, FSX1, DX0, DX1, CLKR0, CLKR1, FSR0, and FSR1.

If $\overline{HCS} = 0$ at device reset, \overline{HRDY} belongs to the high group.

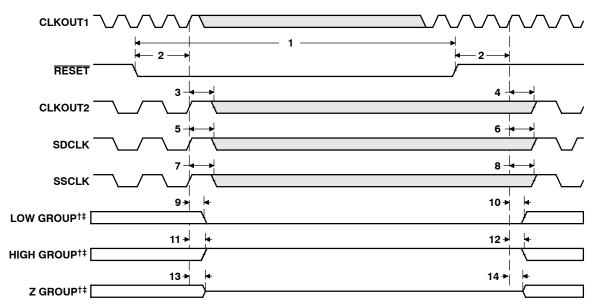
If HCS = 1 at device reset, HRDY belongs to the low group.



[‡] This parameter only applies to CLKMODE x4. The RESET signal is not connected internally to the clock PLL circuit. The PLL, however, may need up to 250 µs to stabilize following device power up or after PLL configuration has been changed. During that time, RESET must be asserted to ensure proper device operation. See the Clock PLL section for PLL lock times.

[¶] HRDY is gated by input HCS.

RESET TIMING (CONTINUED)



 † Low group consists of: IACK, INUM[3:0], DMAC[3:0], PD, TOUT0, and TOUT1

High group consists of: HIN

Z group consists of: EA[21:2], ED[31:0], $\overline{\text{CE}[3:0]}$, $\overline{\text{BE}[3:0]}$, $\overline{\text{ARE}}$, $\overline{\text{AWE}}$, $\overline{\text{AOE}}$, $\overline{\text{SSOE}}$, $\overline{\text{SSWE}}$, $\overline{\text{SDAIO}}$, $\overline{\text{SDRAS}}$, $\overline{\text{SDCAS}}$,

SDWE, HD[15:0], CLKX0, CLKX1, FSX0, FSX1, DX0, DX1, CLKR0, CLKR1, FSR0, and FSR1.

[‡] HRDY is gated by input HCS.

If HCS = 0 at device reset, HRDY belongs to the high group. If HCS = 1 at device reset, HRDY belongs to the low group.

Figure 26. Reset Timing

EXTERNAL INTERRUPT TIMING

timing requirements for interrupt response cycles^{†‡} (see Figure 27)

No			-200		
NO.		MIN	MAX	UNIT	
2	t _{w(ILOW)} Width of the interrupt pulse low	2P		ns	
3	t _{w(IHIGH)} Width of the interrupt pulse high	2P		ns	

[†] Interrupt signals are synchronized internally and are potentially recognized one cycle later if setup and hold times are violated. Thus, they can be connected to asynchronous inputs.

switching characteristics over recommended operating conditions during interrupt response cycles§ (see Figure 27)

NO.	DADAMETED		-200		
	PARAMETER	MIN	MAX	UNIT	
1	t _{d(EINTH-IACKH)} Delay time, EXT_INTx high to IACK high	9P		ns	
4	t _{d(CKO2L-IACKV)} Delay time, CLKOUT2 low to IACK valid	-4	6	ns	
5	t _{d(CKO2L-INUMV)} Delay time, CLKOUT2 low to INUMx valid		6	ns	
6	t _{d(CKO2L-INUMIV)} Delay time, CLKOUT2 low to INUMx invalid	-4		ns	

[§] P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns. When the PLL is used (CLKMODE x4), $0.5P = 1/(2 \times CPU \text{ clock frequency})$.

For CLKMODE x1: 0.5P = PH, where PH is the high period of CLKIN.

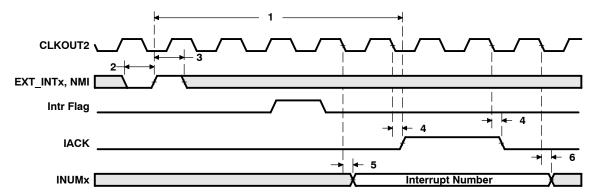


Figure 27. Interrupt Timing

 $^{^{\}ddagger}$ P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

HOST-PORT INTERFACE TIMING

timing requirements for host-port interface cycles^{†‡} (see Figure 28, Figure 29, Figure 30, and Figure 31)

			-200		
NO.			MIN	MAX	UNIT
1	t _{su(SEL-HSTBL)}	Setup time, select signals§ valid before HSTROBE low	4		ns
2	t _{h(HSTBL-SEL)}	Hold time, select signals§ valid after HSTROBE low	2		ns
3	t _{w(HSTBL)}	Pulse duration, HSTROBE low	2P		ns
4	t _{w(HSTBH)}	Pulse duration, HSTROBE high between consecutive accesses	2P		ns
10	t _{su(SEL-HASL)}	Setup time, select signals [§] valid before HAS low	4		ns
11	t _{h(HASL-SEL)}	Hold time, select signals§ valid after HAS low	2		ns
12	t _{su(HDV-HSTBH)}	Setup time, host data valid before HSTROBE high	3		ns
13	t _{h(HSTBH-HDV)}	Hold time, host data valid after HSTROBE high	2		ns
14	t _{h(HRDYL-HSTBL)}	Hold time, HSTROBE low after HRDY low. HSTROBE should not be inactivated until HRDY is active (low); otherwise, HPI writes will not complete properly.	1		ns
18	t _{su(HASL-HSTBL)}	Setup time, HAS low before HSTROBE low	2		ns
19	t _{h(HSTBL-HASL)}	Hold time, HAS low after HSTROBE low	2		ns

[†] HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.

switching characteristics over recommended operating conditions during host-port interface cycles^{†‡} (see Figure 28, Figure 29, Figure 30, and Figure 31)

	PARAMETER		-200		
NO.			MIN	MAX	UNIT
5	t _{d(HCS-HRDY)}	Delay time, HCS to HRDY¶	1	9	ns
6	t _d (HSTBL-HRDYH)	Delay time, HSTROBE low to HRDY high#	3	12	ns
7	toh(HSTBL-HDLZ)	Output hold time, HD low impedance after HSTROBE low for an HPI read	4		ns
8	t _{d(HDV-HRDYL)}	Delay time, HD valid to HRDY low	P - 3	P + 3	ns
9	t _{oh(HSTBH-HDV)}	Output hold time, HD valid after HSTROBE high	2	12	ns
15	t _{d(HSTBH-HDHZ)}	Delay time, HSTROBE high to HD high impedance	3	12	ns
16	t _{d(HSTBL-HDV)}	Delay time, HSTROBE low to HD valid	2	12	ns
17	t _{d(HSTBH-HRDYH)}	Delay time, HSTROBE high to HRDY high	3	12	ns
20	t _{d(HASL-HRDYH)}	Delay time, HAS low to HRDY high	3	12	ns

[†] HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.



[‡] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

[§] Select signals include: HCNTRL[1:0], HR/W, and HHWIL.

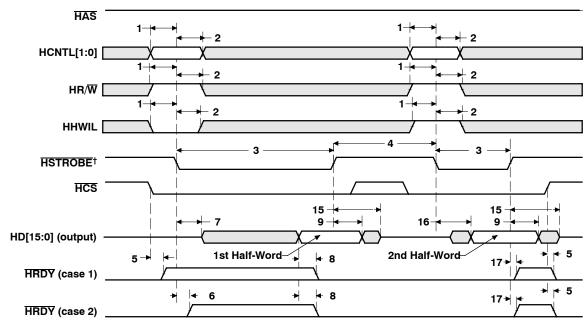
[‡] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

HCS enables HRDY, and HRDY is always low when HCS is high. The case where HRDY goes high when HCS falls indicates that HPI is busy completing a previous HPID write or READ with autoincrement.

[#] This parameter is used during an HPID read. At the beginning of the first half-word transfer on the falling edge of HSTROBE, the HPI sends the request to the DMA auxiliary channel, and HRDY remains high until the DMA auxiliary channel loads the requested data into HPID.

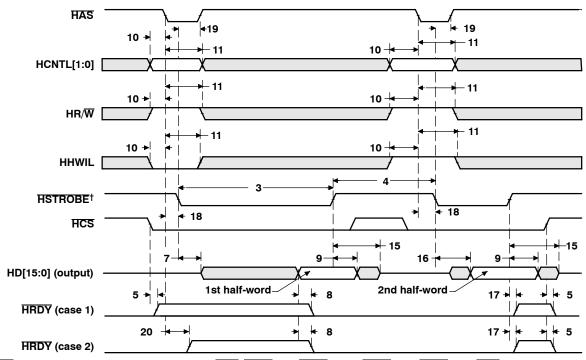
This parameter is used after the second half-word of an HPID write or autoincrement read. HRDY remains low if the access is not an HPID write or autoincrement read. Reading or writing to HPIC or HPIA does not affect the HRDY signal.

HOST-PORT INTERFACE TIMING (CONTINUED)



[†] HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.

Figure 28. HPI Read Timing (HAS Not Used, Tied High)

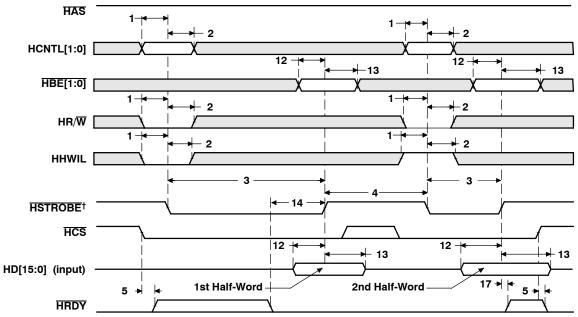


[†] HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.

Figure 29. HPI Read Timing (HAS Used)

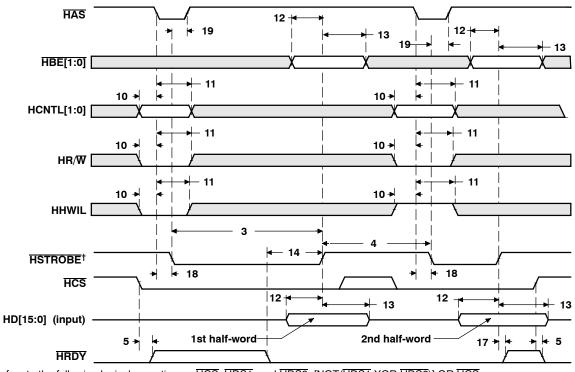


HOST-PORT INTERFACE TIMING (CONTINUED)



[†] HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.

Figure 30. HPI Write Timing (HAS Not Used, Tied High)



[†] HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.

Figure 31. HPI Write Timing (HAS Used)



MULTICHANNEL BUFFERED SERIAL PORT TIMING

timing requirements for McBSP^{†‡}(see Figure 32)

NO				-20	0	
NO.				MIN	MAX	UNIT
2	t _{c(CKRX)}	Cycle time, CLKR/X	CLKR/X ext	2P [§]		ns
3	t _{w(CKRX)}	Pulse duration, CLKR/X high or CLKR/X low	CLKR/X ext	P - 1 [¶]		ns
_		Oak on Aliana and assault EOD blink before OLVD law.	CLKR int	9		
5	t _{su} (FRH-CKRL)	u(FRH-CKRL) Setup time, external FSR high before CLKR low CLKR ext	2		ns	
	t _{h(CKRL-FRH)}	t _{h(CKRL-FRH)} Hold time, external FSR high after CLKR low	CLKR int	6		
6			CLKR ext	3		ns
-		Catua timas DD valid hafara OLKD lavo	CLKR int	8		
7	t _{su(DRV-CKRL)}	Setup time, DR valid before CLKR low	CLKR ext	0		ns
		Halding DD alidaffa OLKD I	CLKR int	3		
8	th(CKRL-DRV)	Hold time, DR valid after CLKR low	CLKR ext	4		ns
40		Oct of the control FOV by by by for OHOV by	CLKX int	9		
10	^t su(FXH-CKXL)	t _{su(FXH-CKXL)} Setup time, external FSX high before CLKX low	CLKX ext	2		ns
- 4.4		Hald time a standal FOV high after OLIVI la	CLKX int	6		
11	th(CKXL-FXH)	Hold time, external FSX high after CLKX low	CLKX ext	3		ns

[†] CLKRP = CLKXP = FSRP = FSXP = 0. If polarity of any of the signals is inverted, then the timing references of that signal are also inverted.

 $^{^{\}ddagger}$ P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

The maximum bit rate for the C6202/02B/03 device is 100 Mbps or CPU/2 (the slower of the two). Care must be taken to ensure that the AC timings specified in this data sheet are met. The maximum bit rate for McBSP-to-McBSP communications is 100 MHz; therefore, the minimum CLKR/X clock cycle is either twice the CPU cycle time (2P), or 10 ns (100 MHz), whichever value is larger. For example, when running parts at 200 MHz (P = 5 ns), use 10 ns as the minimum CLKR/X clock cycle (by setting the appropriate CLKGDV ratio or external clock source). When running parts at 100 MHz (P = 10 ns), use 2P = 20 ns (50 MHz) as the minimum CLKR/X clock cycle. The maximum bit rate for McBSP-to-McBSP communications applies when the serial port is a master of the clock and frame syncs (with CLKR connected to CLKX, FSR connected to FSX, CLKXM = FSXM = 1, and CLKRM = FSRM = 0) in data delay 1 or 2 mode (R/XDATDLY = 01b or 10b) and the other device the McBSP communicates to is a slave.

The minimum CLKR/X pulse duration is either (P-1) or 4 ns, whichever is larger. For example, when running parts at 200 MHz (P = 5 ns), use 4 ns as the minimum CLKR/X pulse duration. When running parts at 100 MHz (P = 10 ns), use (P-1) = 9 ns as the minimum CLKR/X pulse duration.

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

switching characteristics over recommended operating conditions for McBSP^{†‡§} (see Figure 32)

		242445		-200)	
NO.		PARAMETER		MIN	MAX	UNIT
1	t _d (CKSH-CKRXH)	Delay time, CLKS high to CLKR/X high for internal CLKR/X generated from CLKS input		3	10	ns
2	t _{c(CKRX)}	Cycle time, CLKR/X	CLKR/X int	2P [¶]		ns
3	t _{w(CKRX)}	Pulse duration, CLKR/X high or CLKR/X low	CLKR/X int	C - 1.3 [#]	C + 1#	ns
4	t _{d(CKRH-FRV)}	Delay time, CLKR high to internal FSR valid	CLKR int	-2	3	ns
_	1.	Deleviting CHW high to internal FOV valid	CLKX int	-2	3	
9	t _d (CKXH-FXV)	Delay time, CLKX high to internal FSX valid	CLKX ext	3	9	ns
40		Disable time, DX high impedance following last data bit from	CLKX int	-1	4	
12	t _{dis} (CKXH-DXHZ)	CLKX high	CLKX ext	3	9	ns
40		B. L. II. OHAVII L. BY III.	CLKX int	-1	4	
13	t _d (CKXH-DXV)	Delay time, CLKX high to DX valid	CLKX ext	3	9	ns
		Delay time, FSX high to DX valid	FSX int	-1	3	
14	t _{d(FXH-DXV)}	ONLY applies when in data delay 0 (XDATDLY = 00b) mode	FSX ext	3	9	ns

[†] CLKRP = CLKXP = FSRP = FSXP = 0. If polarity of any of the signals is inverted, then the timing references of that signal are also inverted.

 $^{\#}C = H \text{ or } L$

S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

= sample rate generator input clock = P clks if CLKSM = 0 (P clks = CLKS period)

H = CLKX high pulse width = (CLKGDV/2 + 1) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

L = CLKX low pulse width = (CLKGDV/2) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero



[‡] Minimum delay times also represent minimum output hold times.

[§] P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

The maximum bit rate for the C6202/02B/03 device is 100 Mbps or CPU/2 (the slower of the two). Care must be taken to ensure that the AC timings specified in this data sheet are met. The maximum bit rate for McBSP-to-McBSP communications is 100 MHz; therefore, the minimum CLKR/X clock cycle is either twice the CPU cycle time (2P), or 10 ns (100 MHz), whichever value is larger. For example, when running parts at 200 MHz (P = 5 ns), use 10 ns as the minimum CLKR/X clock cycle (by setting the appropriate CLKGDV ratio or external clock source). When running parts at 100 MHz (P = 10 ns), use 2P = 20 ns (50 MHz) as the minimum CLKR/X clock cycle. The maximum bit rate for McBSP-to-McBSP communications applies when the serial port is a master of the clock and frame syncs (with CLKR connected to CLKX, FSR connected to FSX, CLKXM = FSXM = 1, and CLKRM = FSRM = 0) in data delay 1 or 2 mode (R/XDATDLY = 01b or 10b) and the other device the McBSP communicates to is a slave.

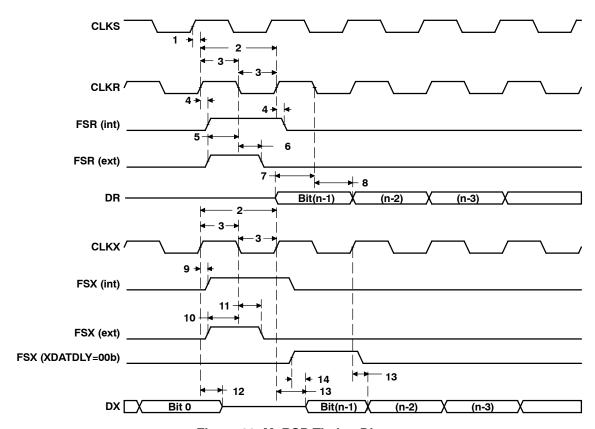


Figure 32. McBSP Timing Diagram

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

timing requirements for FSR when GSYNC = 1 (see Figure 33)

NO.			-20	00	
NO.			MIN	MAX	UNIT
1	t _{su(FRH-CKSH)}	Setup time, FSR high before CLKS high	4		ns
2	t _{h(CKSH-FRH)}	Hold time, FSR high after CLKS high	4		ns

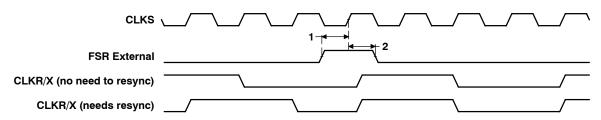


Figure 33. FSR Timing When GSYNC = 1

timing requirements for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = $0^{\dagger \ddagger}$ (see Figure 34)

				-2	00		
NO.			MAST	ER	SLA	/E	UNIT
			MIN	MAX	MIN	MAX	
4	t _{su(DRV-CKXL)}	Setup time, DR valid before CLKX low	12		2 - 3P		ns
5	t _{h(CKXL-DRV)}	Hold time, DR valid after CLKX low	4		5 + 6P		ns

 $[\]overline{}^{\dagger}$ P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

switching characteristics over recommended operating conditions for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = $0^{\dagger \ddagger}$ (see Figure 34)

NO.		MAS	ΓER§	SLAVE		UNIT	
		MIN	MAX	MIN	MAX		
1	t _{h(CKXL-FXL)}	Hold time, FSX low after CLKX low [¶]	T - 2	T + 3			ns
2	t _{d(FXL-CKXH)}	Delay time, FSX low to CLKX high#	L - 2	L + 3			ns
3	t _{d(CKXH-DXV)}	Delay time, CLKX high to DX valid	-2	4	3P + 4	5P + 17	ns
6	t _{dis(CKXL-DXHZ)}	Disable time, DX high impedance following last data bit from CLKX low	L - 2	L + 3			ns
7	t _{dis(FXH-DXHZ)}	Disable time, DX high impedance following last data bit from FSX high			P + 3	3P + 17	ns
8	t _{d(FXL-DXV)}	Delay time, FSX low to DX valid			2P + 2	4P + 17	ns

 $^{^{\}dagger}$ P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

H = CLKX high pulse width = (CLKGDV/2 + 1) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

L = CLKX low pulse width = (CLKGDV/2) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP



[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

[§] S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

⁼ sample rate generator input clock = P_clks if CLKSM = 0 (P_clks = CLKS period)

T = CLKX period = (1 + CLKGDV) * S

FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

[#] FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).

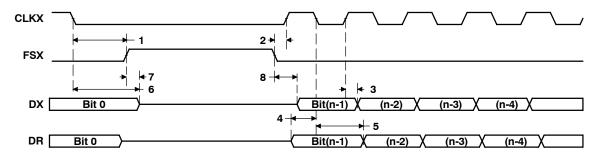


Figure 34. McBSP Timing as SPI Master or Slave: CLKSTP = 10b, CLKXP = 0

timing requirements for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 0^{†‡} (see Figure 35)

				-2	00		
NO.			MAST	ER	SLA	/E	UNIT
			MIN	MAX	MIN	MAX	
4	t _{su(DRV-CKXH)}	Setup time, DR valid before CLKX high	12		2 - 3P		ns
5	t _{h(CKXH-DRV)}	Hold time, DR valid after CLKX high	4		5 + 6P		ns

 $[\]overline{}^{\dagger}$ P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

switching characteristics over recommended operating conditions for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = $0^{\dagger \ddagger}$ (see Figure 35)

NO.		MAS	TER§	SLAVE		UNIT	
			MIN	MAX	MIN	MAX	
1	t _{h(CKXL-FXL)}	Hold time, FSX low after CLKX low [¶]	L - 2	L + 3			ns
2	t _{d(FXL-CKXH)}	Delay time, FSX low to CLKX high#	T - 2	T + 3			ns
3	t _{d(CKXL-DXV)}	Delay time, CLKX low to DX valid	-2	4	3P + 4	5P + 17	ns
6	t _{dis} (CKXL-DXHZ)	Disable time, DX high impedance following last data bit from CLKX low	-2	4	3P + 3	5P + 17	ns
7	t _{d(FXL-DXV)}	Delay time, FSX low to DX valid	H - 2	H + 4	2P + 2	4P + 17	ns

[†] P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

CLKX high pulse width = (CLKGDV/2 + 1) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

L = CLKX low pulse width = (CLKGDV/2) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP



[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

[§] S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

⁼ sample rate generator input clock = P clks if CLKSM = 0 (P clks = CLKS period)

T = CLKX period = (1 + CLKGDV) * S

FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).

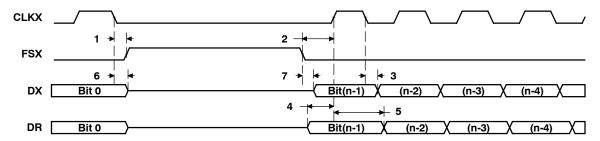


Figure 35. McBSP Timing as SPI Master or Slave: CLKSTP = 11b, CLKXP = 0

timing requirements for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = $1^{+\frac{1}{2}}$ (see Figure 36)

				-2	00		
NO.			MAST	ER	SLAV	/E	UNIT
			MIN	MAX	MIN	MAX	
4	t _{su(DRV-CKXH)}	Setup time, DR valid before CLKX high	12		2 - 3P		ns
5	t _{h(CKXH-DRV)}	Hold time, DR valid after CLKX high	4		5 + 6P		ns

 $^{^{\}dagger}$ P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

switching characteristics over recommended operating conditions for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = 1^{†‡} (see Figure 36)

NO.		PARAMETER	MAS	ΓER§	SLAVE		UNIT
			MIN	MAX	MIN	MAX	
1	t _{h(CKXH-FXL)}	Hold time, FSX low after CLKX high [¶]	T - 2	T + 3			ns
2	t _{d(FXL-CKXL)}	Delay time, FSX low to CLKX low#	H - 2	H + 3			ns
3	t _{d(CKXL-DXV)}	Delay time, CLKX low to DX valid	-2	4	3P + 4	5P + 17	ns
6	t _{dis(CKXH-DXHZ)}	Disable time, DX high impedance following last data bit from CLKX high	H - 2	H + 3			ns
7	t _{dis(FXH-DXHZ)}	Disable time, DX high impedance following last data bit from FSX high			P + 3	3P + 17	ns
8	t _{d(FXL-DXV)}	Delay time, FSX low to DX valid			2P + 2	4P + 17	ns

[†] P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

H = CLKX high pulse width = (CLKGDV/2 + 1) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

= (CLKGDV/2) * S if CLKGDV is even L = CLKX low pulse width

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

[#] FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).



[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

[§] S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

⁼ sample rate generator input clock = P_clks if CLKSM = 0 (P_clks = CLKS period)

T = CLKX period = (1 + CLKGDV) * S

FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

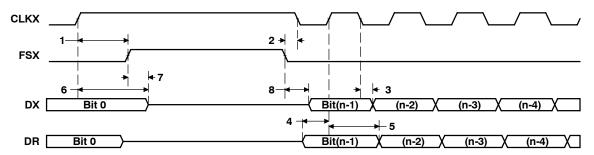


Figure 36. McBSP Timing as SPI Master or Slave: CLKSTP = 10b, CLKXP = 1

timing requirements for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = $1^{\dagger \pm}$ (see Figure 37)

				-2	00		
NO.			MAST	ER	SLA	/E	UNIT
			MIN	MAX	MIN	MAX	
4	t _{su(DRV-CKXL)}	Setup time, DR valid before CLKX low	12		2 - 3P		ns
5	t _{h(CKXL-DRV)}	Hold time, DR valid after CLKX low	4		5 + 6P		ns

 $^{^{\}dagger}$ P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

switching characteristics over recommended operating conditions for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 1^{†‡} (see Figure 37)

NO.	PARAMETER			ΓER§	SLA	UNIT	
		MIN	MAX	MIN	MAX		
1	t _{h(CKXH-FXL)}	Hold time, FSX low after CLKX high [¶]	H - 2	H + 3			ns
2	t _{d(FXL-CKXL)}	Delay time, FSX low to CLKX low#	T - 2	T + 1			ns
3	t _{d(CKXH-DXV)}	Delay time, CLKX high to DX valid	-2	4	3P + 4	5P + 17	ns
6	t _{dis(CKXH-DXHZ)}	Disable time, DX high impedance following last data bit from CLKX high	-2	4	3P + 3	5P + 17	ns
7	t _{d(FXL-DXV)}	Delay time, FSX low to DX valid	L - 2	L + 4	2P + 2	4P + 17	ns

[†] P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

CLKX high pulse width = (CLKGDV/2 + 1) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

L = CLKX low pulse width = (CLKGDV/2) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP



[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

[§] S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

⁼ sample rate generator input clock = P clks if CLKSM = 0 (P clks = CLKS period)

T = CLKX period = (1 + CLKGDV) * S

FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).

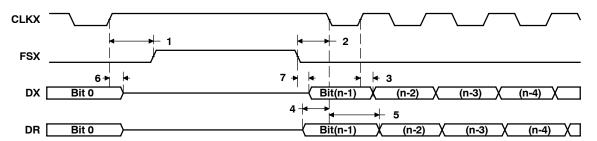


Figure 37. McBSP Timing as SPI Master or Slave: CLKSTP = 11b, CLKXP = 1

DMAC, TIMER, POWER-DOWN TIMING

switching characteristics over recommended operating conditions for DMAC outputs (see Figure 38)

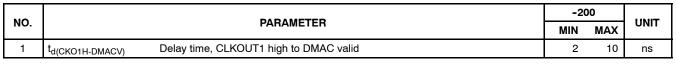




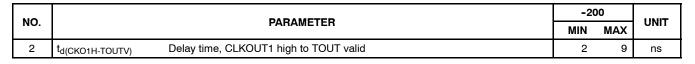
Figure 38. DMAC Timing Diagram

timing requirements for timer inputs[†] (see Figure 39)

		-20	0	
NO.			MAX	UNIT
1	t _{w(TINP)} Pulse duration, TINP high or low	2P		ns

 $^{^{\}dagger}$ P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

switching characteristics over recommended operating conditions for timer outputs (see Figure 39)



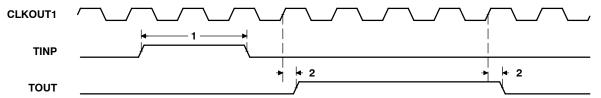
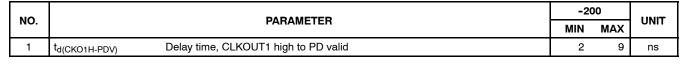


Figure 39. Timer Timing Diagram

switching characteristics over recommended operating conditions for power-down outputs (see Figure 40)



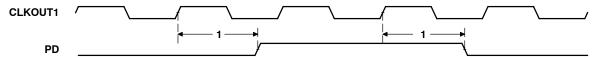


Figure 40. Power-Down Timing



JTAG TEST-PORT TIMING

timing requirements for JTAG test port (see Figure 41)

NO		-20			
NO.			MIN	MAX	UNIT
1	t _{c(TCK)}	Cycle time, TCK	35		ns
3	t _{su(TDIV-TCKH)}	Setup time, TDI/TMS/TRST valid before TCK high	10		ns
4	t _{h(TCKH-TDIV)}	Hold time, TDI/TMS/TRST valid after TCK high	9		ns

switching characteristics over recommended operating conditions for JTAG test port (see Figure 41)

NC		PARAMETER			
INC	•	PARAMETER	MIN	MAX	UNIT
2	t _d (TCKL-TDOV)	Delay time, TCK low to TDO valid	-3	12	ns

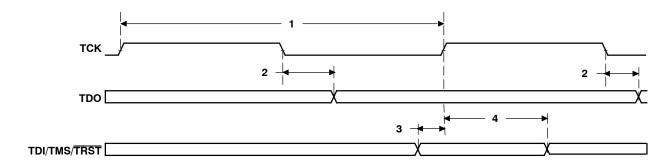


Figure 41. JTAG Test-Port Timing Diagram

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PACKAGING INFORMATION

Orderable part number	Status (1)	Material type	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
SM320C6201GJCA20EP	Obsolete	Production	FCBGA (GJC) 352	-	-	Call TI	Call TI	-40 to 105	SM320C6201GJCA 20EP 320C6201

⁽¹⁾ Status: For more details on status, see our product life cycle.

- (3) RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.
- (4) Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.
- (5) MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.
- (6) Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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